



SCALING in THERMAL SYSTEMS

Herbert Shea
micro-470

Outline – Thermal Scaling Chapter

- Heat transfer in solid
- Heat conduction in a gas
- Radiation
- Thermal Time constants
- ElectroThermal Actuators

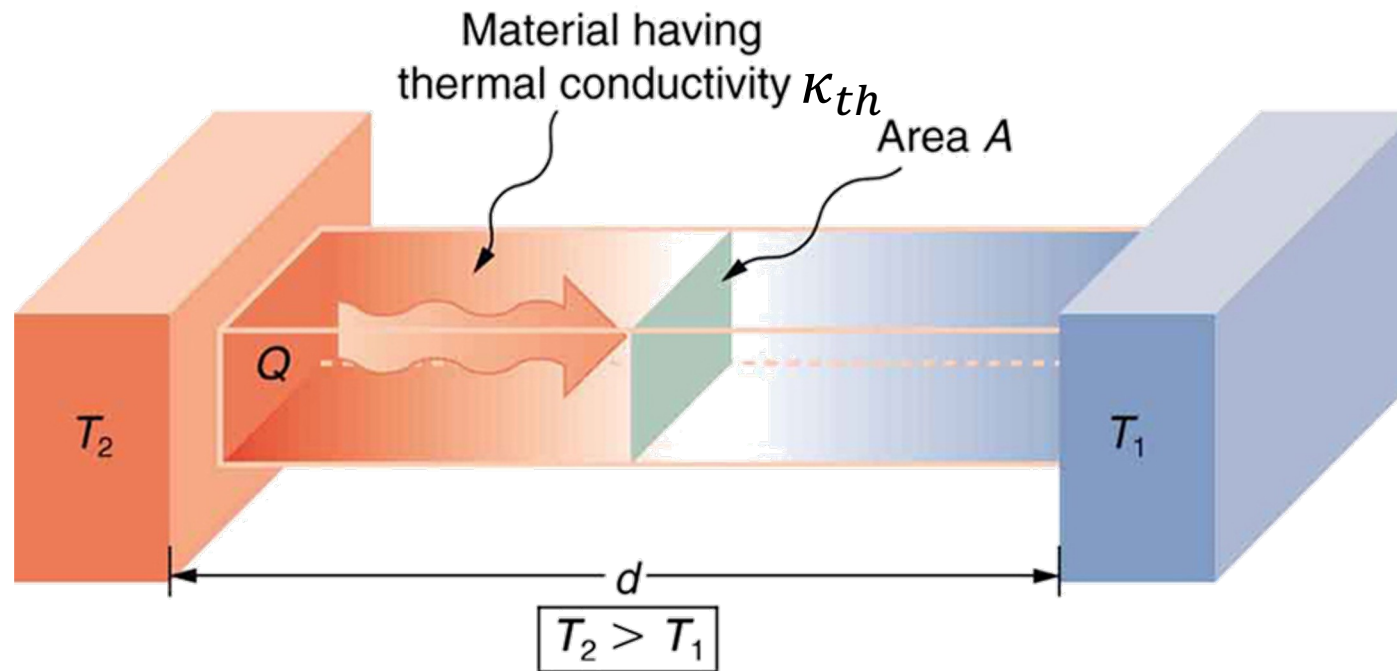


Concepts to master in Thermal systems

- Thermal transport by conduction in solid
 - RC model of thermal time constant
 - scaling of R_{th} (or G_{th}) and c_{th}
- Thermal transport by conduction in a gas: length scale at which dominant
- Radiative heat transport, and scaling in small gaps
- Temperature profile along a uniformly heated wire for : a) only conduction, and b) conduction and convection
- Dynamics of thermal system in 1D
- How thermal accelerometer works
- How thermal inkjet works
- Electrothermal actuators
 - Main geometries (bimorph, hot/cold arm, chevron)
 - Energy density
 - efficiency

Heat conduction (ignoring radiation and convection for now)

- As soon as we put two elements with different temperatures in contact: we get a heat flux from the warmer side to the cooler one.
- Equilibrium state: temperature gradient (if both temperatures T_1 and T_2 are fixed)

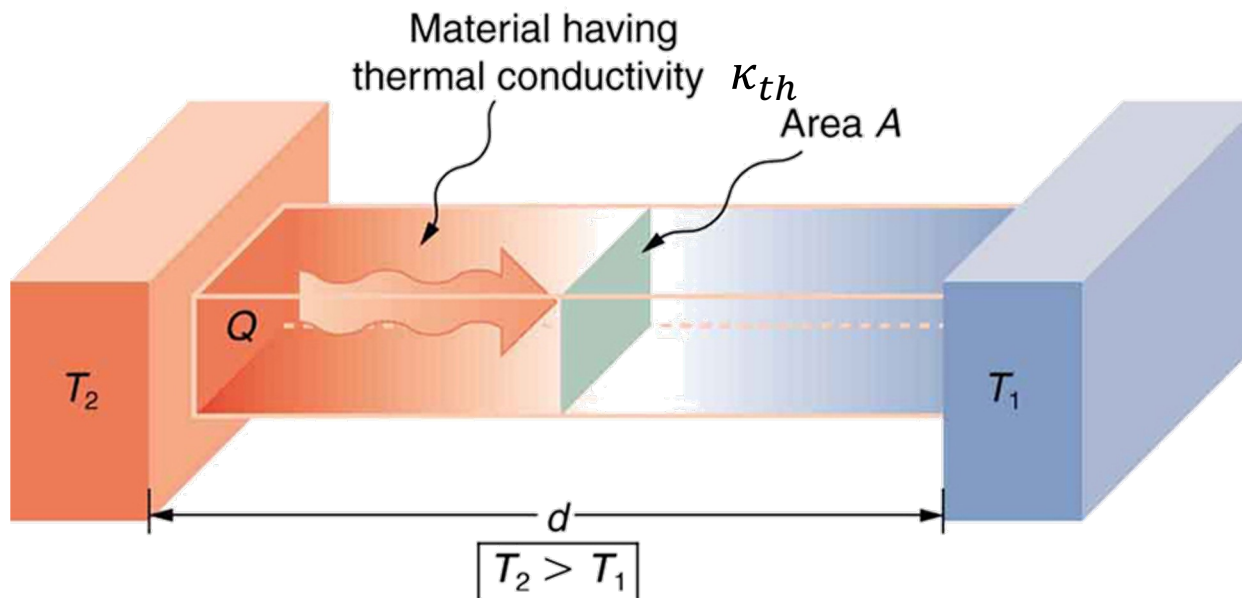


Heat conduction between 2 objects

- Heat flux is given by Fourier's law:

$$\vec{q} = -\kappa_{th} \vec{\nabla} T$$

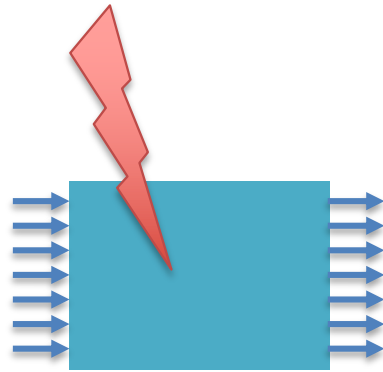
$$\dot{Q}_A = \vec{q} \cdot \vec{A} = -\kappa_{th} \vec{\nabla} T \cdot \vec{A}$$



- q : rate of flow of thermal energy per unit area [$\text{W} \cdot \text{m}^{-2}$]
- Q is the internal energy [J]
- dQ/dt is amount of heat transferred per unit time in [W]
- κ_{th} is thermal conductivity in [$\text{W}/(\text{m} \cdot \text{K})$]
- c_v is specific heat capacity [$\text{J}/(\text{kg} \cdot \text{K})$]
- C is heat capacity [J/K]
- A is area [m^2]
- T is temperature [K]

1D heat flux with distributed heat source $q(x)$

- 1D Temperature $T(x,t)$ distribution given by:



$$\kappa_{th} A \frac{d^2 T(x)}{dx^2} + q_{source}(x) = \rho A c_v \frac{\partial T}{\partial t}$$

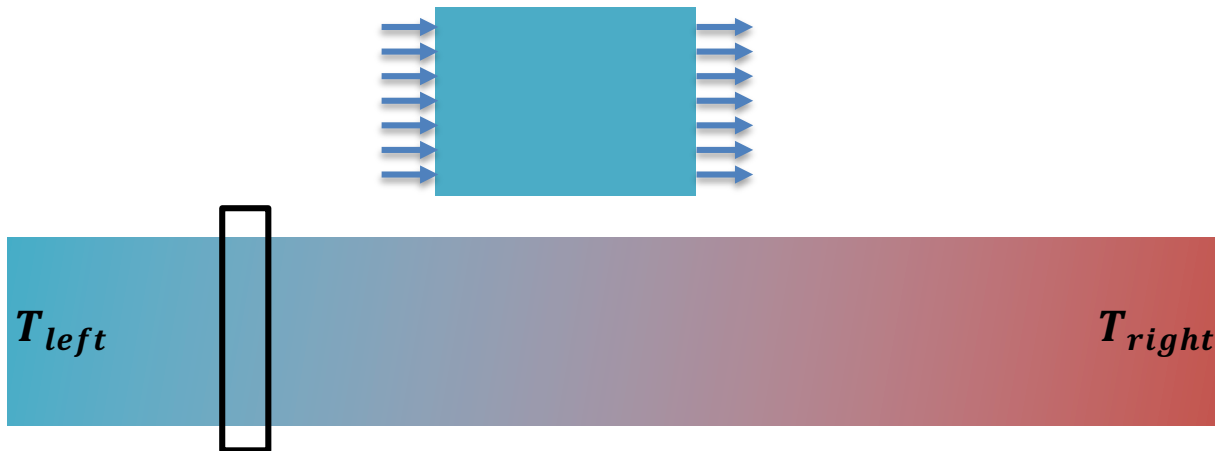


Steady state, 1D, no heat source

$$\kappa_{th} A \frac{d^2 T(x)}{dx^2} + \cancel{q_{source}(x)} = \cancel{\rho A c_v \frac{\partial T}{\partial t}}$$

$$\kappa_{th} A \frac{d^2 T(x)}{dx^2} = 0 \quad \rightarrow \quad T(x) = ax + b$$

$$T(x) - T(0) = \frac{x}{L} \Delta T$$



constant heat flow:

$$\dot{Q}_A = -\frac{\kappa_{th}}{L} \Delta T$$

Thermal
resistance

$$R_{th} = \frac{L}{A \kappa_{th}}$$

$\propto L^{-1}$

Thermal
conductance

$$G_{th} = \frac{A \kappa_{th}}{L}$$

$\propto L$

Transient state (time-dependence), no source

- Temperature gradient:

$$\kappa_{th} A \frac{\partial^2 T(x, t)}{\partial x^2} + \cancel{q_{source}(x)} = \rho A c_v \frac{\partial T}{\partial t}$$

$$\frac{\partial^2 T(x, t)}{\partial x^2} = \frac{\rho c_v}{\kappa_{th}} \frac{\partial T}{\partial t} \longrightarrow \text{Partial derivatives make analytical solution a bit cumbersome}$$



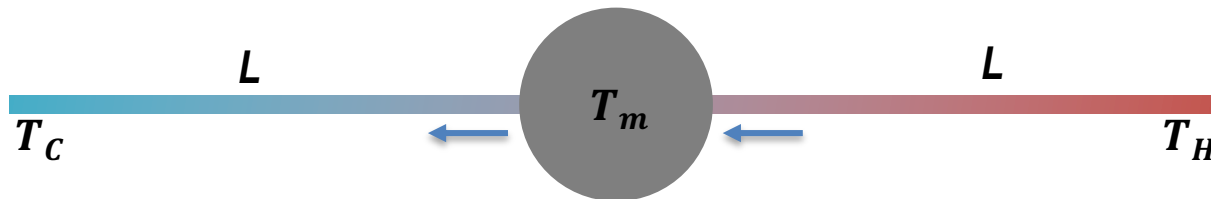
$$\frac{\kappa_{th}}{\rho c_v}$$

Thermal diffusivity:
ability of an object to
take heat out



Transient state for small mass with long anchors

- For a mass that is spatially small compared to the thermal links, we can calculate the transient easily if we assume the mass has no temperature gradient (=lumped):



$$\dot{Q}_{out} = \frac{\kappa_{th}}{L} A (T_m - T_c)$$

$$\dot{Q}_{in} = \frac{\kappa_{th}}{L} A (T_H - T_m)$$

$$\dot{Q}_{in} - \dot{Q}_{out} = \frac{\kappa_{th}}{L} A (T_H + T_c - 2T_m) = m \cdot c_v \frac{\partial T_m}{\partial t}$$

$$T_m(t) = \frac{T_H + T_c}{2} \left(1 - e^{-\frac{t}{\tau}} \right)$$

$$\tau = \frac{\rho c_v L \cdot Vol}{2 \kappa_{th} A} \propto L^2$$

Time constant

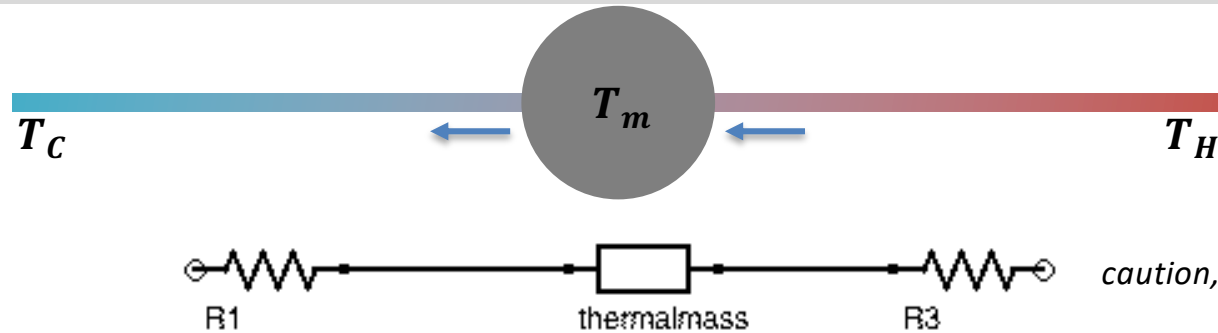
$$\tau = RC$$

$$C_{th} = \rho Vol \cdot c_v = m c_v \propto L^3$$

$$R_{th} = \frac{L}{\kappa_{th} A} \propto L^{-1}$$

Initial conditions: $T_m(t=0) = 0$, and T_{hot} and T_{cold}

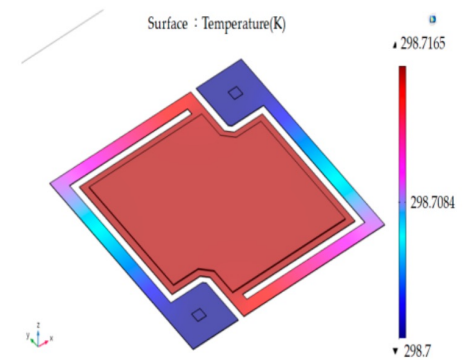
What allowed us to do this lumping?



caution, not electrical equivalent circuit !

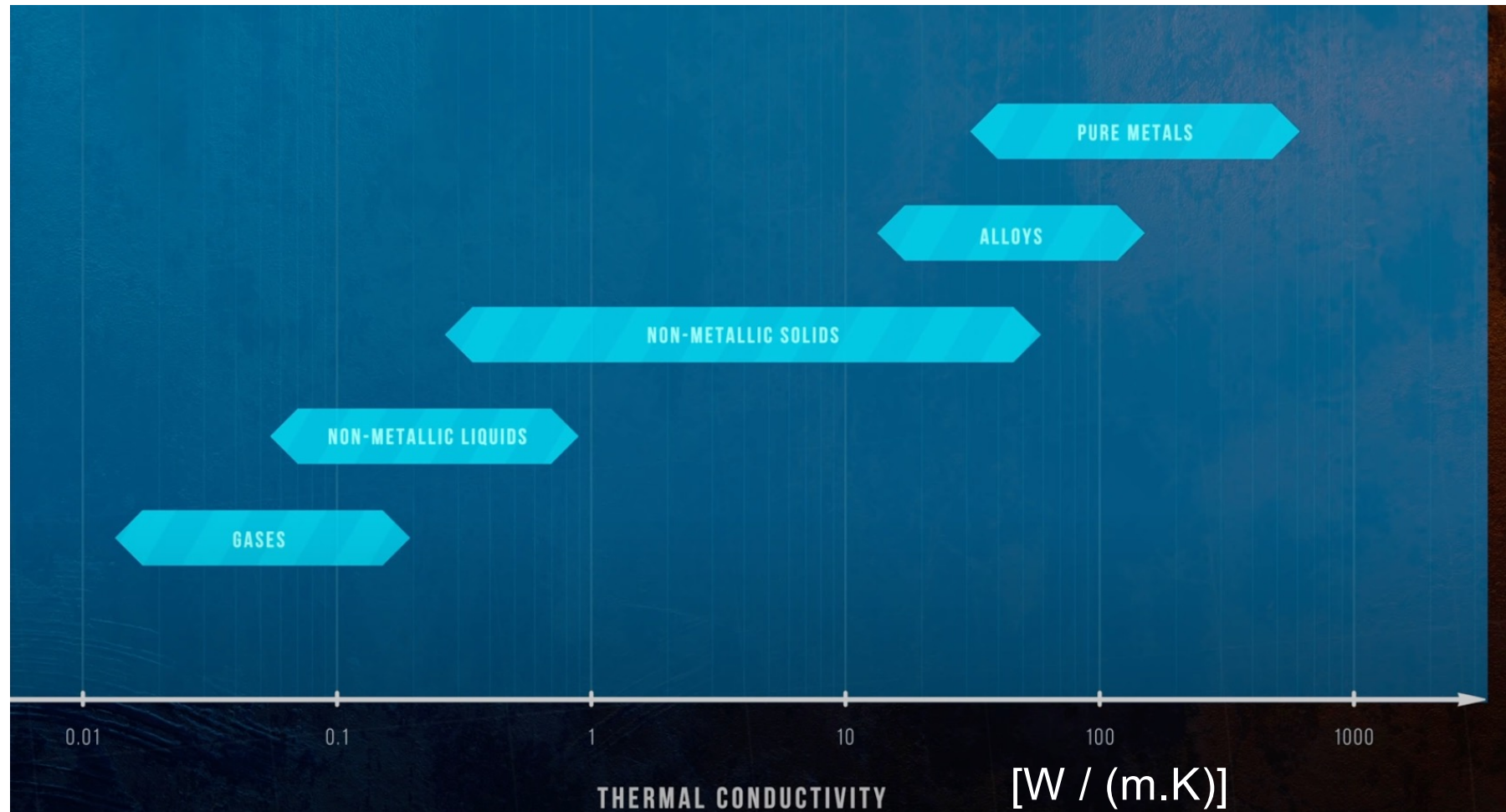
- We got rid of the partial derivatives $\frac{\partial^2 T(x,t)}{\partial x^2}$ by assuming the temperature in the middle region is uniform and by ignoring thermal mass of links
- This is only true if $\left(\frac{\kappa_{th}}{L} A\right)_{link} \ll \left(\frac{\kappa_{th}}{L} A\right)_{middle}$
- In other words: $R_{th,links} \gg R_{th,middle\ mass}$

Temperature of a bolometer plate



Uniform plate temperature due to cooling by conduction in arms

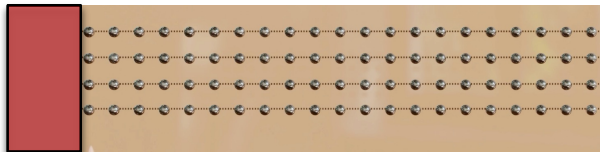
Thermal conductivity is a materials property



<https://www.youtube.com/watch?v=6jQsLAqrZGQ>

Thermal conductivity in solids

Dielectric



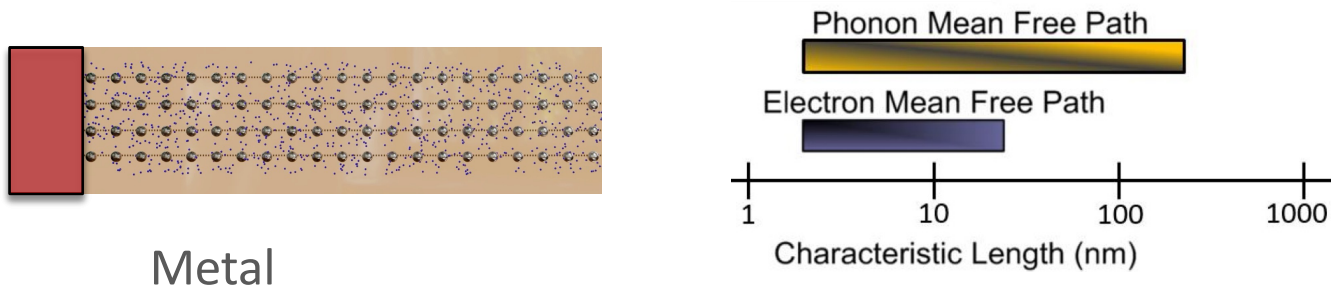
$$k_{th} = \frac{1}{3} c v \lambda$$

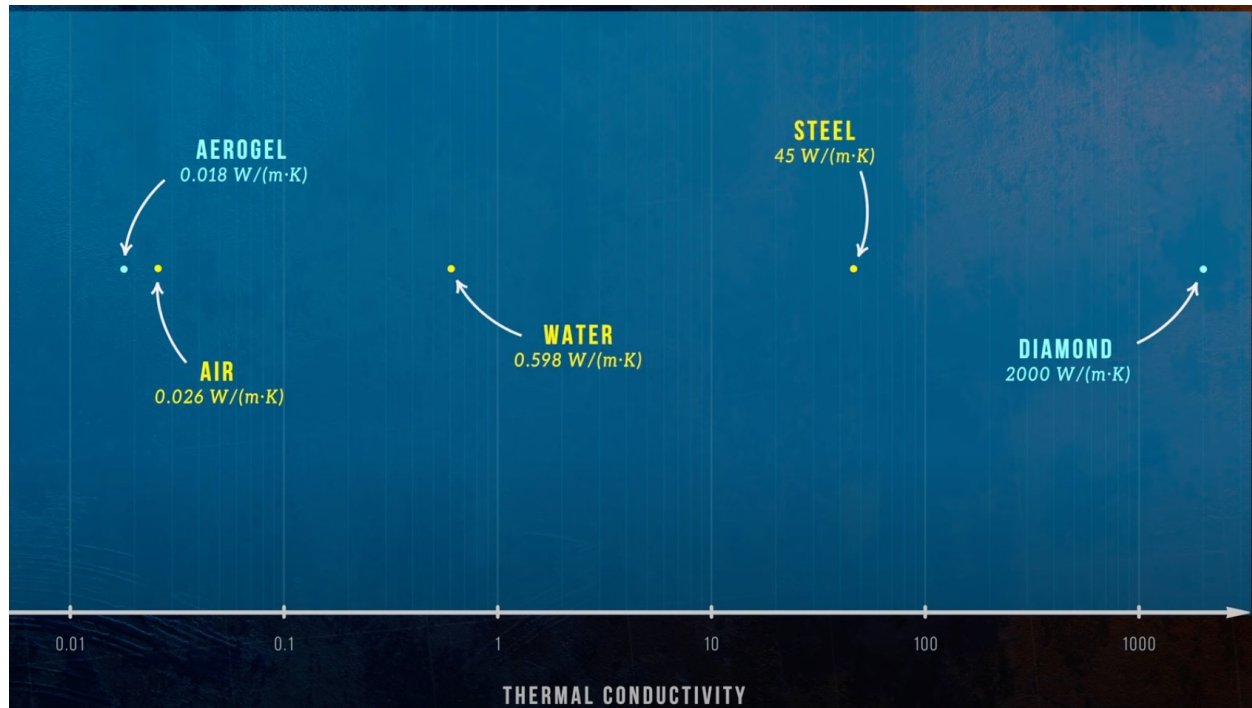
specific heat capacity

phonon group velocity

phonon mean free path

	<u>metals:</u>	<u>dielectrics and semiconductors:</u>
specific heat c:	c _e for electrons	c _s for phonons
molecular velocity v:	electron Fermi velocity v _e =1.4 10 ⁶ m/s	sound velocity v _s =10 ³ m/s
average mean free path:	λ _e = 1 to 10 nm	phonons λ _s =0.1 μm to 1 μm





Conductivity Numbers are
for dimensions $\gg 1 \mu m$

		Thermal conductivity	Specific heat capacity	density
		k_{th} [W/m K]	c_v [J/kg K]	ρ [kg/m ³]
Gas	Air	0.024	1005	1.2
	He	0.14	5200	0.17
Liquids	Water	0.59	4200	1000
	Ethanol	0.18	2200	1100
Solids	Silicon	170	691	2300
	Al	235	879	3750
	Ni	91	444	8880
	SiO ₂	1.3	840	2660

Thermal conductivity: lower in thin films and nanowires than in bulk

Phonon-boundary **scattering** reduces the bulk phonon mean free path (MFP) and thus reduces thermal conductivity.

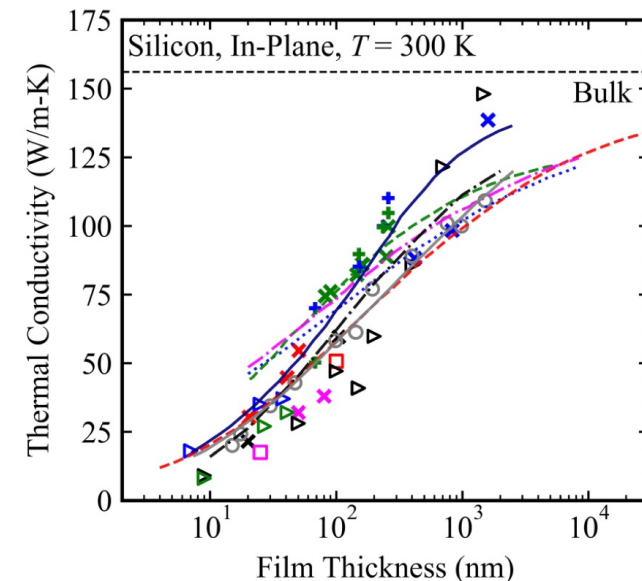
Empirical correction factor in thin films
(phonon confinement effect):

$$\frac{k_{th}^*}{k_{th}} = 1 - \frac{\lambda}{3h}$$

h: thickness

Example:

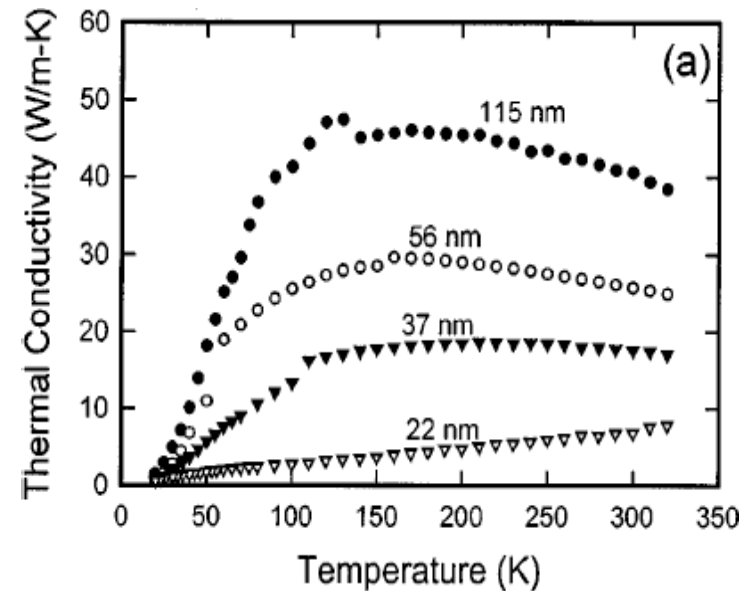
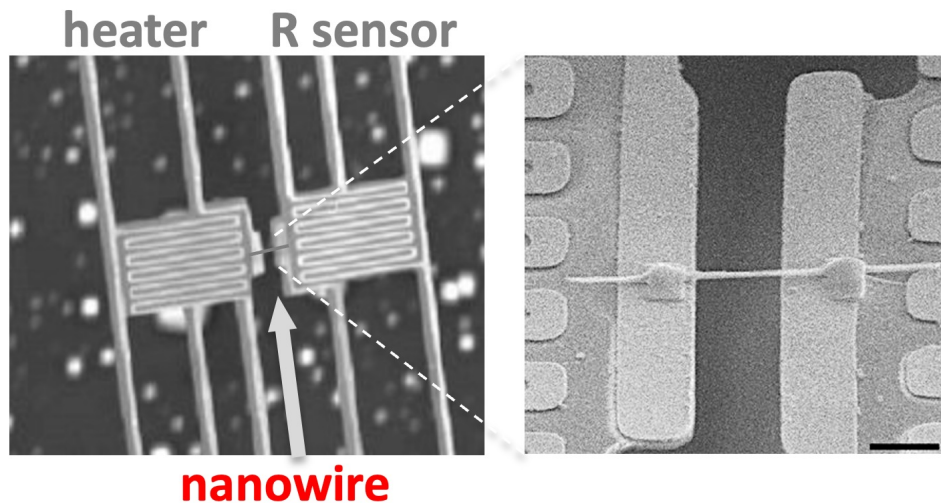
a silicon film of 0.2 microns has a correction factor of 0.83
(MFP in Si ~ 100 nm)



Fu et al. PHYSICAL REVIEW B 101, 045417 (2020)

The reduction of the phonon (lattice) thermal conductivity in thin films and nanowires is a result of the **phonon-boundary scattering** and **phonon spatial confinement** effects.

How can one measure the thermal conductivity of nanowires ?



At Room T, κ drops as size drops

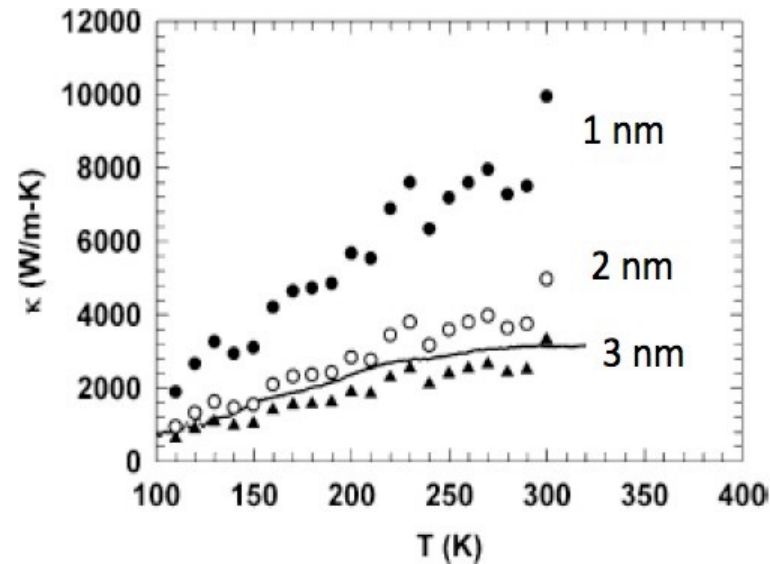
Effect of surface roughness:

- enhanced **boundary scattering** has a strong effect on phonon transport in Si nanowires

D. Li et al, Applied Physics Letters 83 (2003)

HOWEVER; Thermal conductivity is high in carbon nanotubes (CNT) and graphene

i) long range crystallinity,
ii) long phonon mean free path, and
iii) high speed of sound of the CNTs
lead to the high thermal conductivity of CNTs



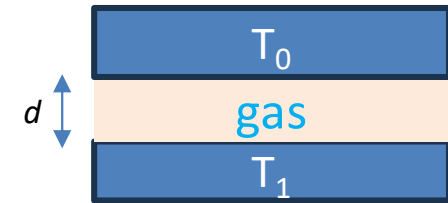
sample type	K (W/mK)
SLG	~4840–5300
MW-CNT	> 3000
SW-CNT	~3500
SW-CNT	1750–5800

This is in sharp contrast with the reduced phonon thermal conductivity of other nanowires and thin films !!

Nano Lett., Vol. 8, No. 3, 2008

Thermal conduction in a Gas (no convection, no radiation)

Heat flow between two parallel plates: $Q_{th} = \Delta T \frac{\kappa_{th} A}{d}$ $Q = [W]$
A: area



Thermal conductance per surface unit: $g_{th} = \frac{\kappa_{th}}{d} \left[\frac{W}{m^2 \cdot K} \right]$

This result **neglects convection** and **radiation**

Air: $\kappa_{th,air} = 0.024$ W/mK at 1 bar, room temperature. (for He: 0.14 W/mK)

Scaling of conduction: $g_{th} \propto L^{-1}$

(this breaks down when $d = 0$, as we then have bulk conductivity of the walls)

Small gap limit for gas thermal conduction

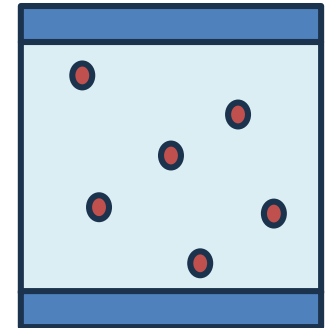
The thermal conductivity of the gas must be corrected when the gap is of order the molecular mean free path λ .

The mean free path of molecules in air (at room pressure and temperature) : $\lambda_{1atm} = 66 \text{ nm}$

An empirical rule for thermal conductance between parallel plates with d spacing:

$$g_{th} = \frac{Q_{th}}{\Delta T \cdot A} = \frac{\kappa_{th}}{d + 6\lambda} \quad [W/m^2 K]$$

Ie, the effective thermal conductance in Knudsen (free molecule) regime becomes almost independent of distance.



Heat Convection

- Heat transfer due to movement of surrounding fluid

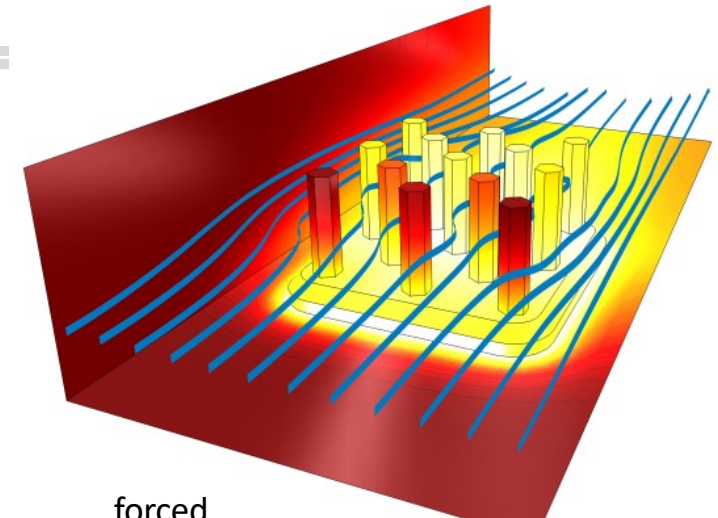
$$\frac{dQ}{dt} = h \cdot A (T_{body} - T_{\infty})$$

$h \rightarrow$ heat transfer coefficient $\left[\frac{W}{m^2 K} \right]$

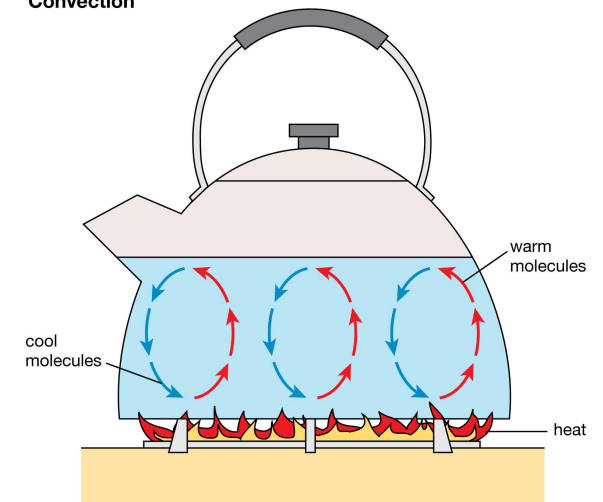
$$R_{th,convection} = \frac{1}{Ah}$$

$$G_{th,convection} = Ah$$

- Typical values for free convection in air of h are between $2 \text{ W} / \text{m}^2 \text{ K}$ and $25 \text{ W} / \text{m}^2 \text{ K}$
- We will often use $10 \text{ W} / \text{m}^2 \text{ K}$



forced
Convection



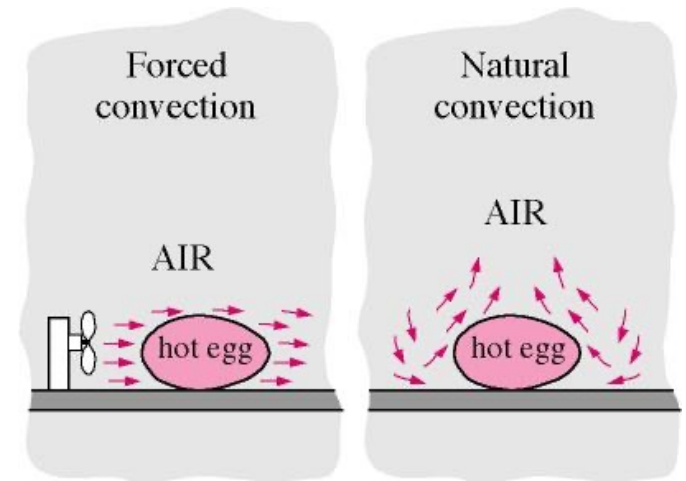
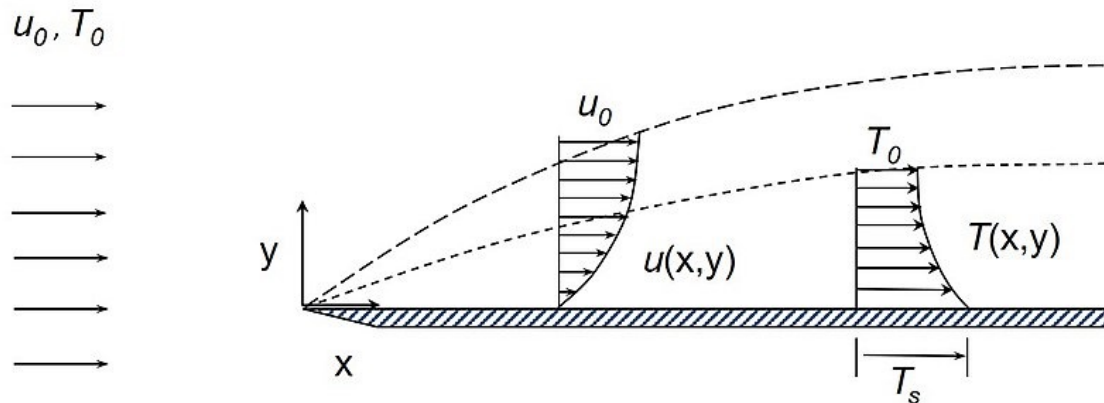
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Heat transfer by convection in a gas (air)

- Natural convection depends on density change:
needs gravity
e.g. Vertical plate vs horizontal plate, not
same convection
- Forced convection (fan)

For What happens to convection when systems are scaled
down?

=> The thermal boundary layer depends on scale



$$\delta_T = 5 \sqrt{x \frac{\kappa_{th}}{\rho u_0 c_p}}$$

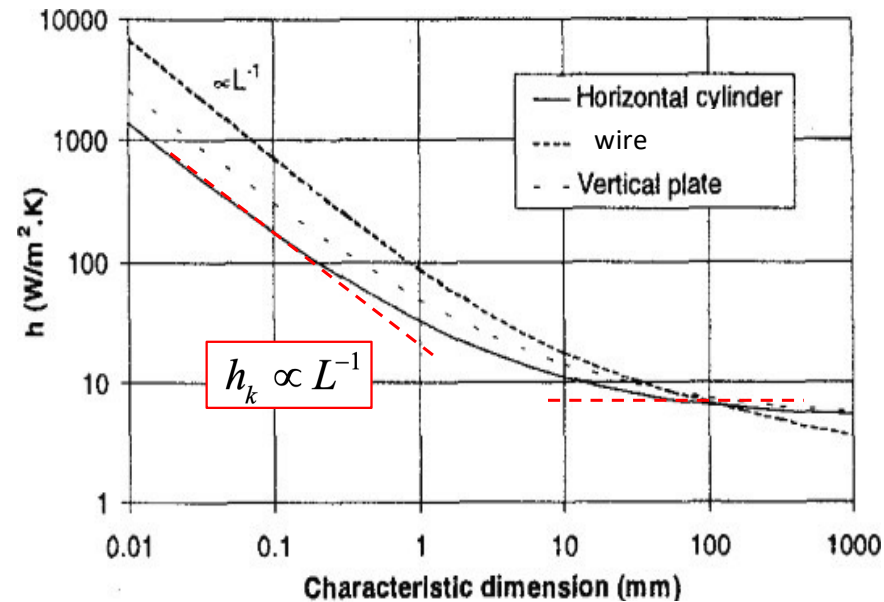
https://en.m.wikipedia.org/wiki/Thermal_boundary_layer_thickness_and_shape

Convection in thin wires and plates

Heat exchange by air convection becomes very efficient in small structures (if they are far from walls)

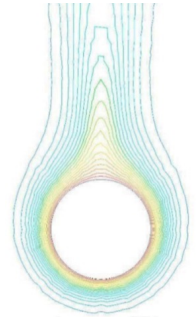
$$h_k = \left(2.68 + \frac{0.11}{\sqrt{d}} \right)^2$$

$$h_k \propto L^{-1}$$



for large d: $h_k \rightarrow 2.68^2 \approx 7$

h_k is independent of size if $d > 10$ mm



However: the behavior of free convection also depends on size of cavities around the element. In a small cavity, the Re number is small => less convective flow
So we do not see this enhancement in MEMS

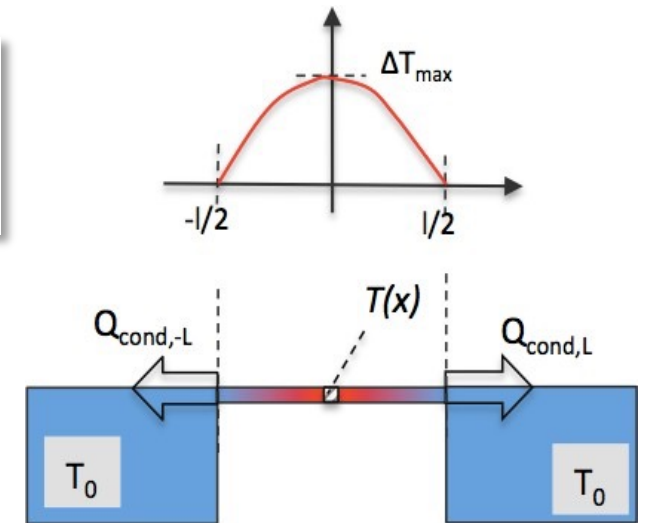
Peirs, J.; Reynaerts, D.; Van Brussel, H., "Scale effects and thermal considerations for micro-actuators," *Robotics and Automation*, 1998. Proceedings. 1998

Temperature profile of uniformly heated beam (only conduction to anchors)

- **only conduction along beam**
- **no convection and no radiation losses.**
- **Uniform heating along the beam (eg Joule heating along the wire)**
- **Thermally clamped at both ends $T_{\text{end}}=T_0$**

$$\frac{\partial^2 T}{\partial x^2} = -\frac{q_{in}}{\kappa_{th}}$$

$$T \text{ profile (at equilibrium): } \Delta T(x) = \frac{q_{in}}{2\kappa_{th}} \left(\left(\frac{l}{2} \right)^2 - x^2 \right)$$



$$\Delta T_{max} = \frac{q_{in} l^2}{8 \kappa_{th}} \propto L^2$$

@ cst power density

q_{in} = internal heating power $[W \cdot m^{-3}]$

Numerical examples:

beam: $l=500 \mu\text{m}$, $w=20 \mu\text{m}$, $e=1 \mu\text{m}$ $q_{in}=10^{12} \text{ W/m}^3$ this is $P=10 \text{ mW}$ total power

Silicon beam $\kappa_{th}=170 \text{ W/m.K}$

$\Delta T_{max} = 184 \text{ K (ie } T=200^\circ\text{C)}$

Same total power (10 mW), longer beam ($l=1\text{mm}$)

$\Delta T_{max} = 368 \text{ K}$

Platinum beam, $500 \mu\text{m}$, $\kappa_{th}=76 \text{ W/Km}$

$\Delta T_{max} = 411 \text{ K}$

**Easy to heat small structures
to high T with little power !**

Temperature profile of uniformly heated beam with convection **and** with conduction

- **Convection and conduction along beam** ($L \times b \times h$)
- **No radiative losses.**
- **Uniform heating along the beam** (eg Joule heating along the wire)
- **Thermally clamped at both ends** $T = T_0$

$$\cancel{\rho c \frac{\partial T}{\partial t}} = \kappa_{th} \frac{\partial^2 T}{\partial x^2} + q_{in} - Y(x)$$

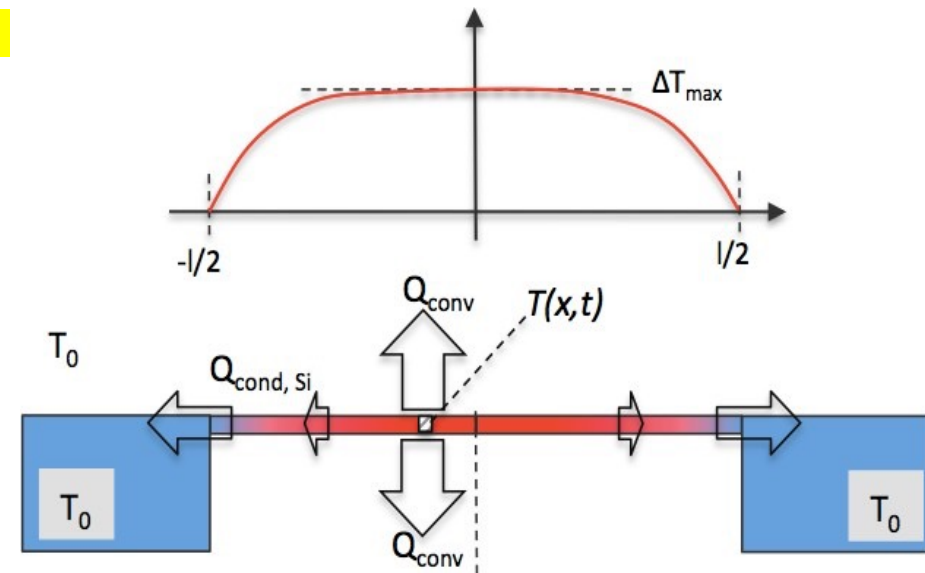
Convection:

$$Y(x) = 2 \frac{h_k L b T}{V} = 2 \frac{h_k L b T}{L b h} = \frac{2}{h} h_k T(x)$$

$$\frac{\partial^2 T}{\partial x^2} + \frac{q_{in}}{\kappa_{th}} - \frac{2h_k}{\kappa_{th}h} T(x) = 0$$

more info in : Ki Bang Lee, *Principles of Microelectromechanical Systems*, Wiley, 2011

q_{in} = internal heating power [$W \cdot m^{-3}$] $q_{in} = \rho_{el} j^2$
 $Y(x)$ = losses [$W \cdot m^{-3}$] convection and radiation losses



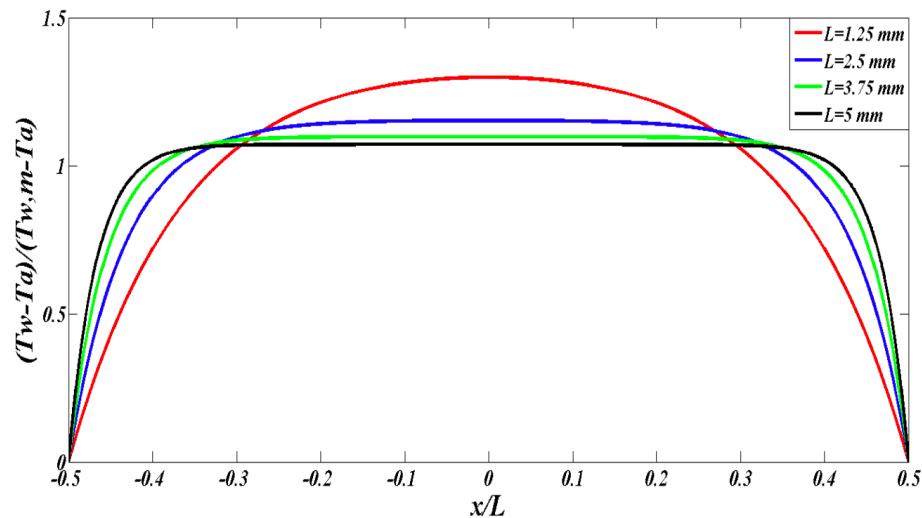
General solution:

$$T(x) = C_1 e^{\Gamma x} + C_2 e^{-\Gamma x} + C_3$$

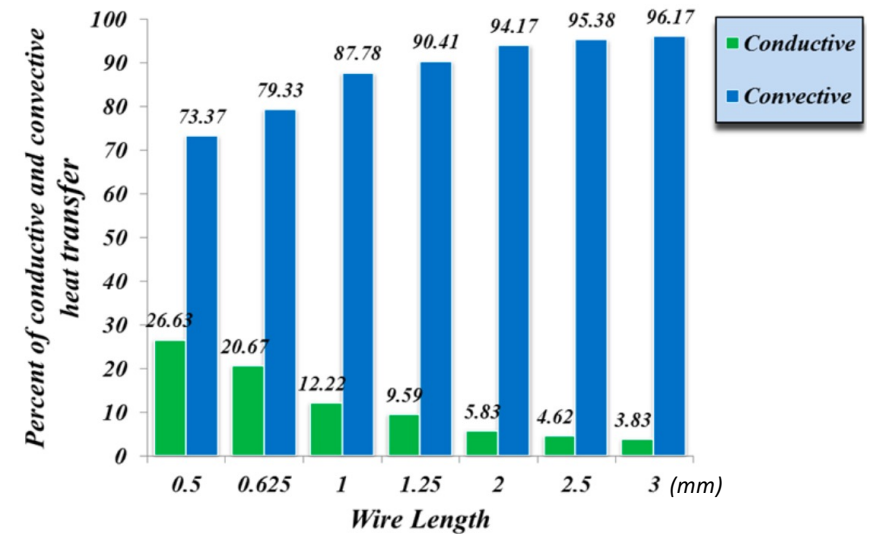
with $C_3 = \frac{q_{in} e}{2h_k}$ and

$$C_1 = C_2 = -\frac{q_{in} e}{2\lambda_k} \cdot \frac{1}{(e^{\Gamma l/2} + e^{-\Gamma l/2})}$$

Temperature profile of a uniformly heated wire (doubly clamped, T_0 at each end)



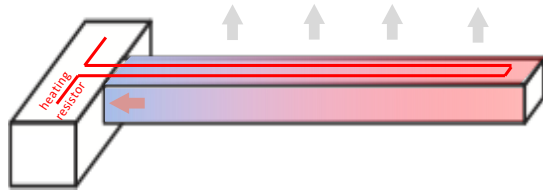
ΔT_{max} lower when convection
than when only conduction



- Diameter of wire is 5 μm
- Air velocity is 20 m/s
- Wire far from any wall

Dehghan M and Kazemi M (2012) "Analytical and Experimental Investigation About Heat Transfer of Hot-Wire Anemometry. An Overview of Heat Transfer Phenomena." InTech.
<http://dx.doi.org/10.5772/51989>.

Temperature profile of a cantilever, with conduction along a beam and **FORCED** convection in air

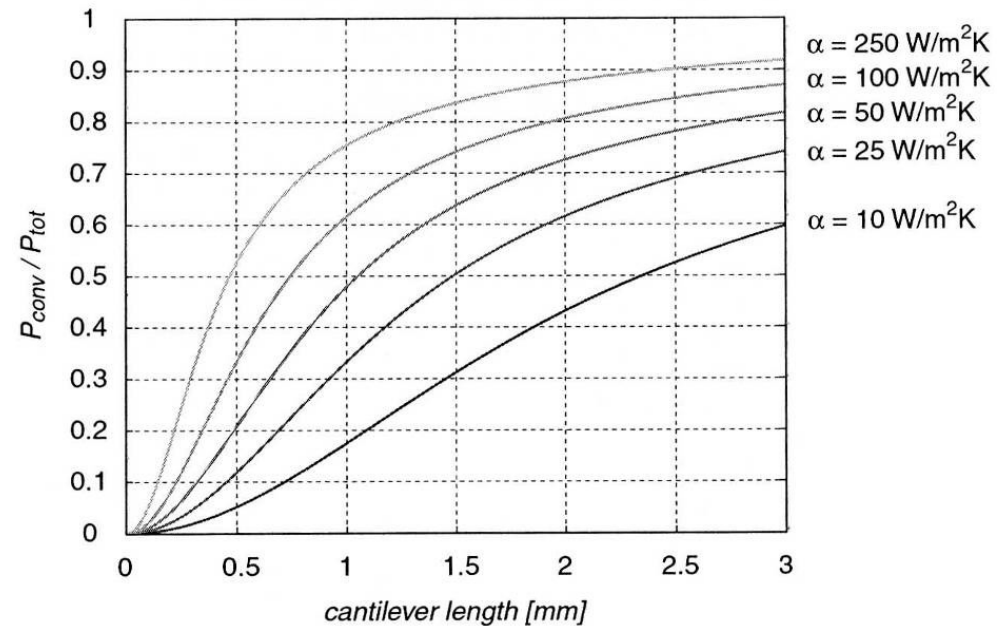


Numerical example:

Thickness $h=1\text{ }\mu\text{m}$, Nickel
Convection coeff: $h_k=10\text{ W/m}^2\text{K}$

$l=1\text{ mm}$ $\Rightarrow P_{conv}/P_{tot}=18\%$

$l=0.3\text{ mm}$ $\Rightarrow P_{conv}/P_{tot}=3\%$



Simply supported beam, uniformly (Joule) heating: computed relative convection losses for different convection coefficients. (radiation is neglected)

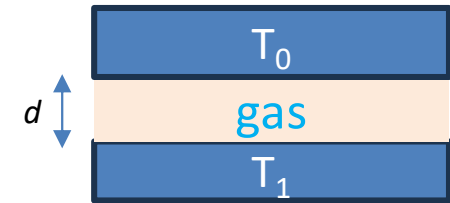
From G. Lammel thesis, EPFL

Conclusion: In short beams (typ. below $500\text{ }\mu\text{m}$), **convection** in air can be **neglected**.

In MEMS, conduction generally dominates

Conduction vs convection in MEMS

What is the “Equivalent gap” for which losses from conduction are equal to losses from convection ($h_k=10 \text{ W/m}^2\text{K}$) ?



$$q_{th} = \kappa_{th} \frac{\Delta T}{d} = h_k \Delta T$$

→ for gaps thinner than 1 mm, the main thermal transfer mechanism is typically conduction, rather than convection in the air gap.

$$d_0 = \frac{\kappa_{th}}{h_k} = \frac{0.024}{10} = 2.4 \text{ mm}$$

This is Nusselt Number =1

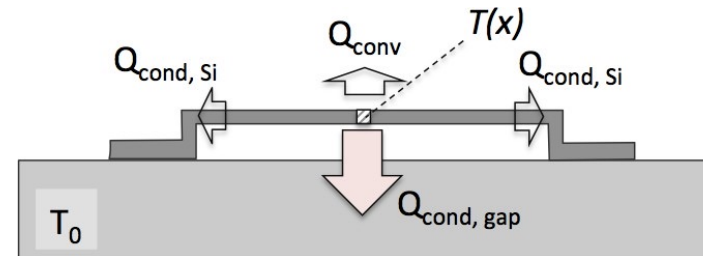
$$Nu = \frac{\text{convection}}{\text{conduction}} = \frac{h_k}{k_{th}/L} = \frac{h_k L}{k_{th}}$$

Heated beam/plate near a surface

$$Q_{gap,cond} = \Delta T \frac{\kappa_{th,air}}{d} A$$

$$= \Delta T \frac{\kappa_{th,air}}{d} l b$$

$$\Delta T = \frac{Q_{gap} \cdot d}{k_{th} \cdot l \cdot b}$$



Numerical example:

power 10 mW, $l=500 \mu\text{m}$, $b=20 \mu\text{m}$ $d=2 \mu\text{m}$

$\Rightarrow \Delta T = 83 \text{ } ^\circ\text{C}$

The conduction along the beam model gave $\Delta T_{\max}=184 \text{ } ^\circ\text{C}$ for a beam far away from the surface (i.e., when losses are dominated by conduction along the beam)

An air gap of $2 \mu\text{m}$ has a thermal conductance (per area) of $\mathbf{g_{th, conduction,area} = 10^4 \text{ W/m}^2\text{K}}$

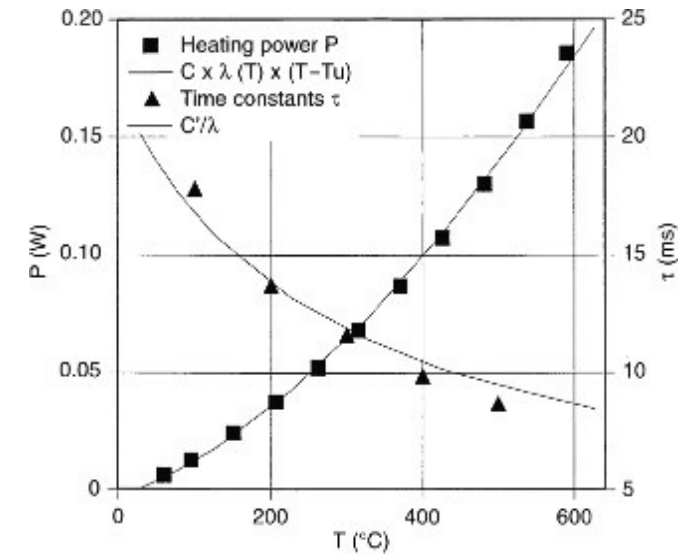
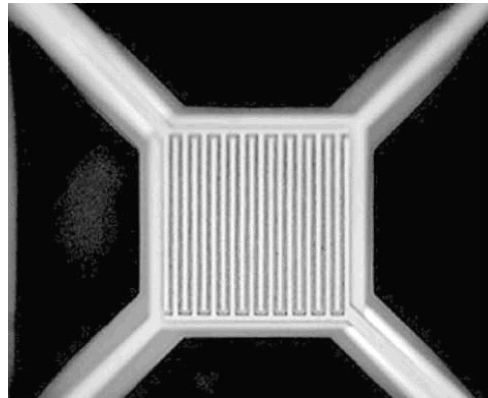
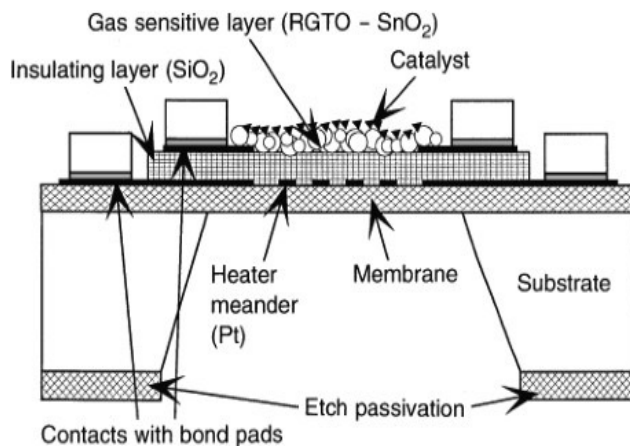
Compare this to unforced convection of about $\mathbf{g_{th, convection,area} = 10 \text{ W/m}^2\text{K}}$

$\Rightarrow$ for gaps thinner than 1 mm, conduction through the air gap is typically the main thermal transfer mechanism

Microhotplates: suspended by narrow hinges to minimize heat loss

Gas sensors (semiconductor SnO_2 and catalytic) are based on the use of surfaces heated to 200-400 °C

To decrease the heat losses, the plate consists of a **thin dielectric membrane** with thin-film metal heaters.



The **time constant** is directly **related** to the **heat losses** ($\tau = RC$, see elsewhere in this chapter).

If we want to rapidly modulate the temperature (which is useful in some detection modalities), there will be a **trade-off** between heat loss and time constant.

Low heat loss (by conduction): thin long arms. $R_{th} = \frac{L}{A \kappa_{th}}$

Thermal accelerometer – based on convection

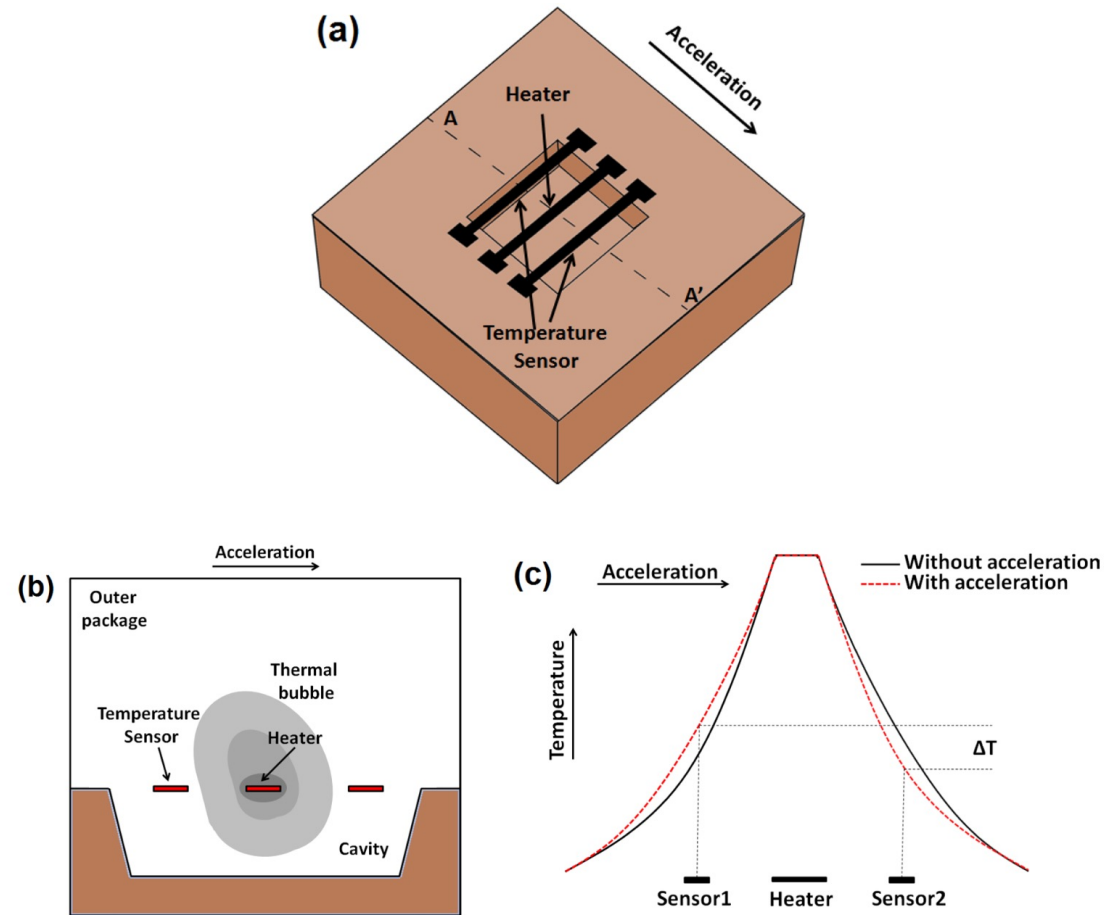
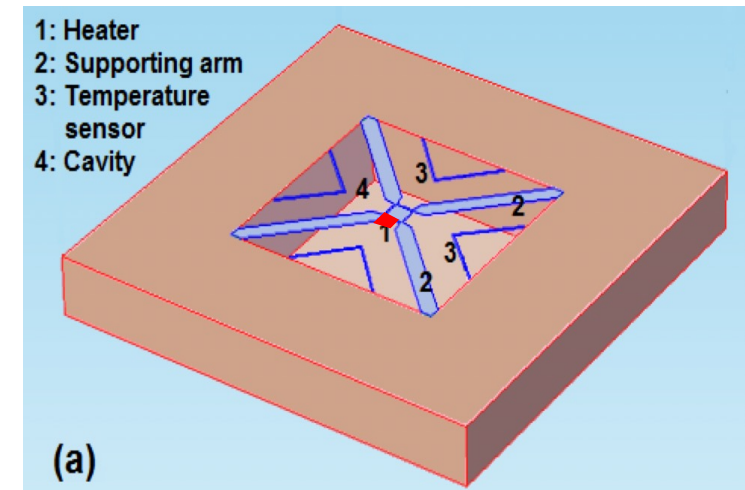


Figure 1. (a) Schematic view of thermal accelerometer, (b) cross-sectional view along AA' line, and (c) temperature profile along AA'.

R. Mukherjee, J. Basu, P. Mandal, P. K. Guha, A review of micromachined thermal accelerometers.
J. Micromech. Microeng. **27**, 123002 (2017).



Low Power :

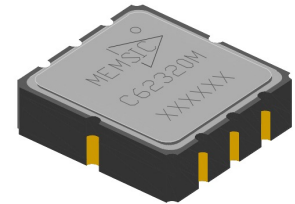
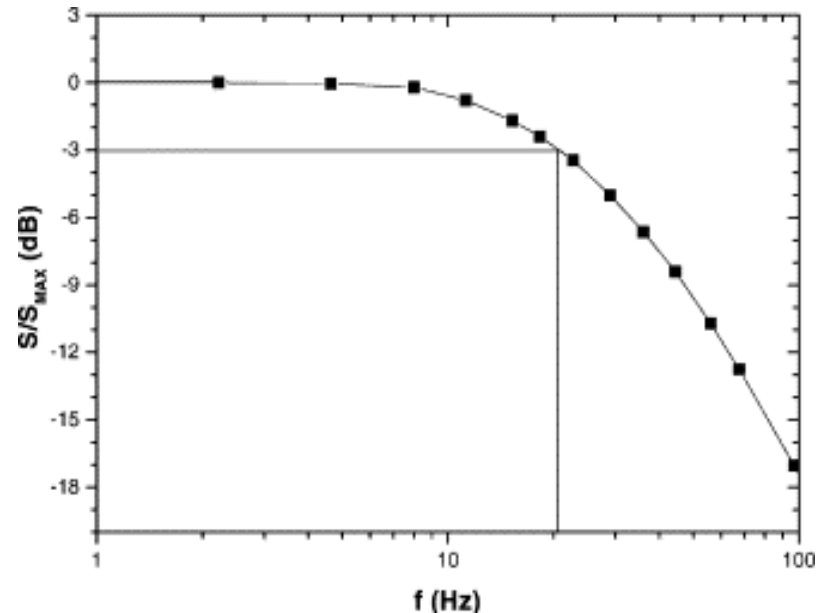
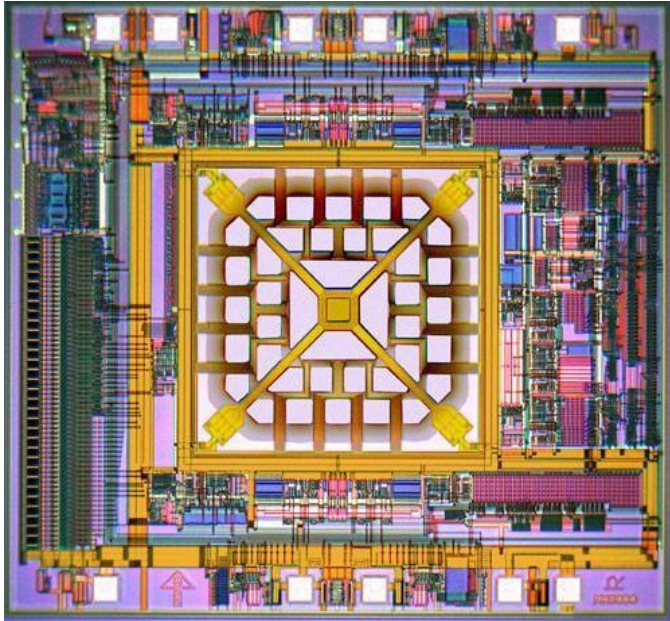
- need suspended heater
- low thermal conductance to the walls

But for fast response :

- high thermal conductance of fluid
- low mass of heater

Typically 50 mW, 20 Hz, sensitivity 10^{-2} ms^{-2}

2-axis Thermal accelerometer



$$\begin{aligned}\tau_{convection} &= RC \\ &\approx \frac{\rho c_v V}{Ah} \\ &= \frac{\rho c_v d}{h} \sim L\end{aligned}$$

h : heat transfer coefficient
 d : height of cavity

To improve the bandwidth:

- i) the cavity size should be made small and
- ii) thermal diffusivity of the working fluid must be high.

But this leads to higher power consumption and lower resolution.

MEMSIC developed this concept for commercial use. CMOS integration (excellent circuit, but limits materials choice, especially for sensors). Power consumption is rather high (several mW), long turn-on time (300 ms) — excellent shock resistance

<https://www.memsic.com/thermal-accelerometer>

	Thermal accelerometer	Capacitive accelerometer
Model number	MXR9500MZ	ADXL327
Sensitivity	500 mV g ⁻¹	420 mV g ⁻¹
Bandwidth	17 Hz	550/1600 Hz
Full scale range	±1.5 g	±2 g
Nonlinearity	0.5% of full scale	±0.2% of full scale
RMS noise density	0.6/0.9 mg (√Hz) ⁻¹	0.25 mg (√Hz) ⁻¹
Cross-axis sensitivity	±2%	±1%
Mechanical shock survival	50 000 g	10 000 g
Supply current	4.2mA at 3.0 V	350 μA at 3.0 V
Package dimension	7 mm × 7 mm × 1.8 mm	4 mm × 4 mm × 1.45 mm

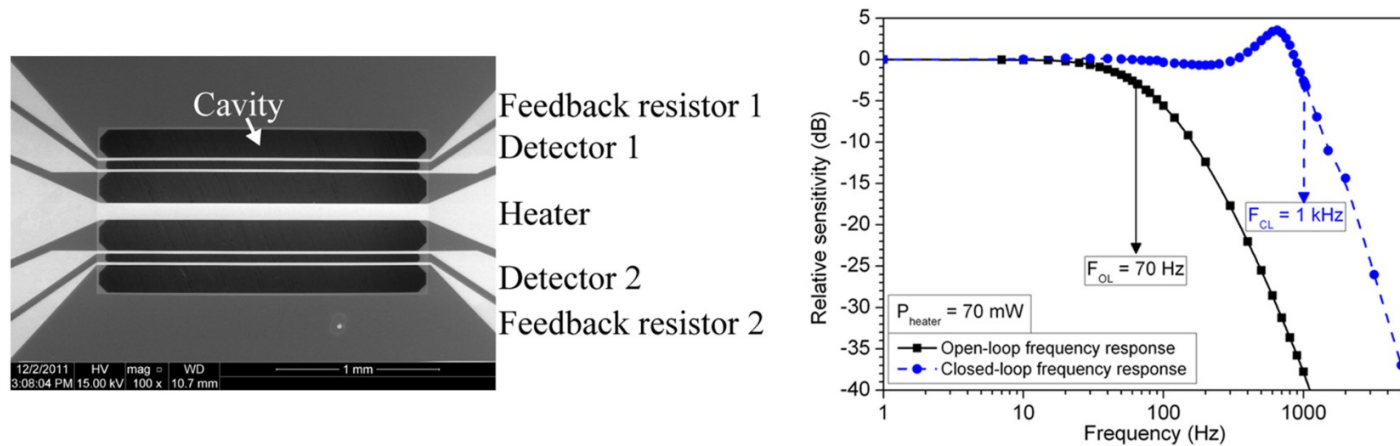


Figure 11. Scanning electron microscope image and measured frequency response of convective accelerometer with thermal feedback arrangement. Reproduced with permission from [91].

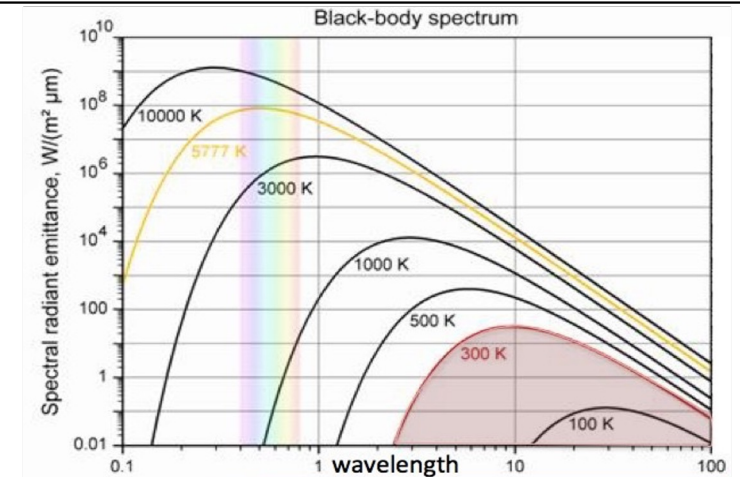
R. Mukherjee, J. Basu, P. Mandal, P. K. Guha, A review of micromachined thermal accelerometers. *J. Micromech. Microeng.* **27**, 123002 (2017).

Radiative heat transfer

Black body radiation

$$Q_{th} = A\varepsilon\sigma T^4 \quad [\text{W}] \quad \text{with } \sigma = 5.7 \cdot 10^{-8} \frac{\text{W}}{\text{m}^2 \text{K}^4}$$

ε : emissivity; A: Area of source
 σ Stefan–Boltzmann constant



radiative conductance:

$$G_{th} = \frac{dQ_{th}}{dT} = 4A\varepsilon T^3 = 4A\varepsilon(T_1^3 - T_2^3)$$

$G_{th} [\text{W/K}]$

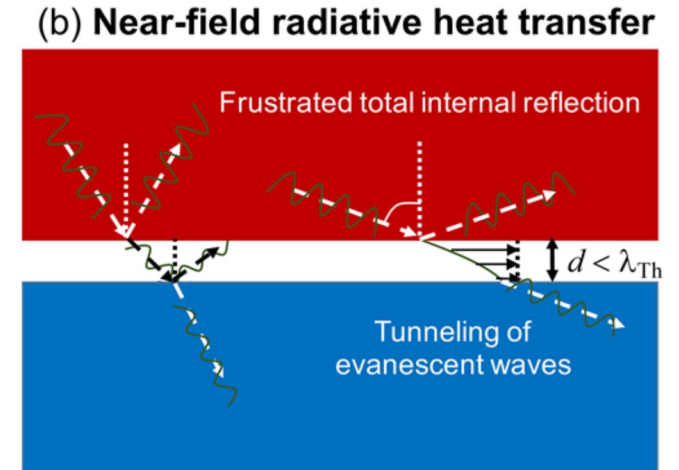
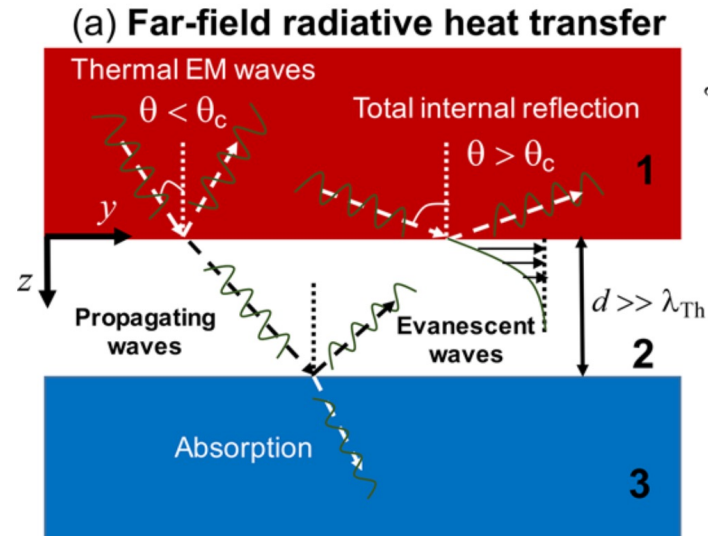
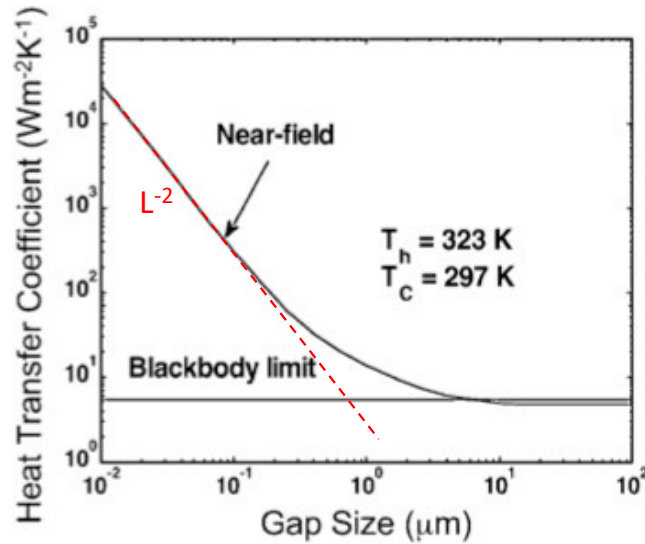
- heat flux is **independent of distance d for parallel plates**
- heat transfer coefficient is approximately **5 W/m² K** at ambient temperature (black body)
 - i.e. comparable to convection

Planck's law assumes all dimensions > 10 μm !

When the distance d becomes comparable to the maximum **wavelength** of the Planck blackbody spectrum (approx 10 μm at room temperature), then the radiative transfer coefficient depends on d .

Radiative heat transfer in very small gaps

J. C. Cuevas, F. J. García-Vidal, Radiative Heat Transfer. *ACS Photonics*. **5**, 3896–3915 (2018)



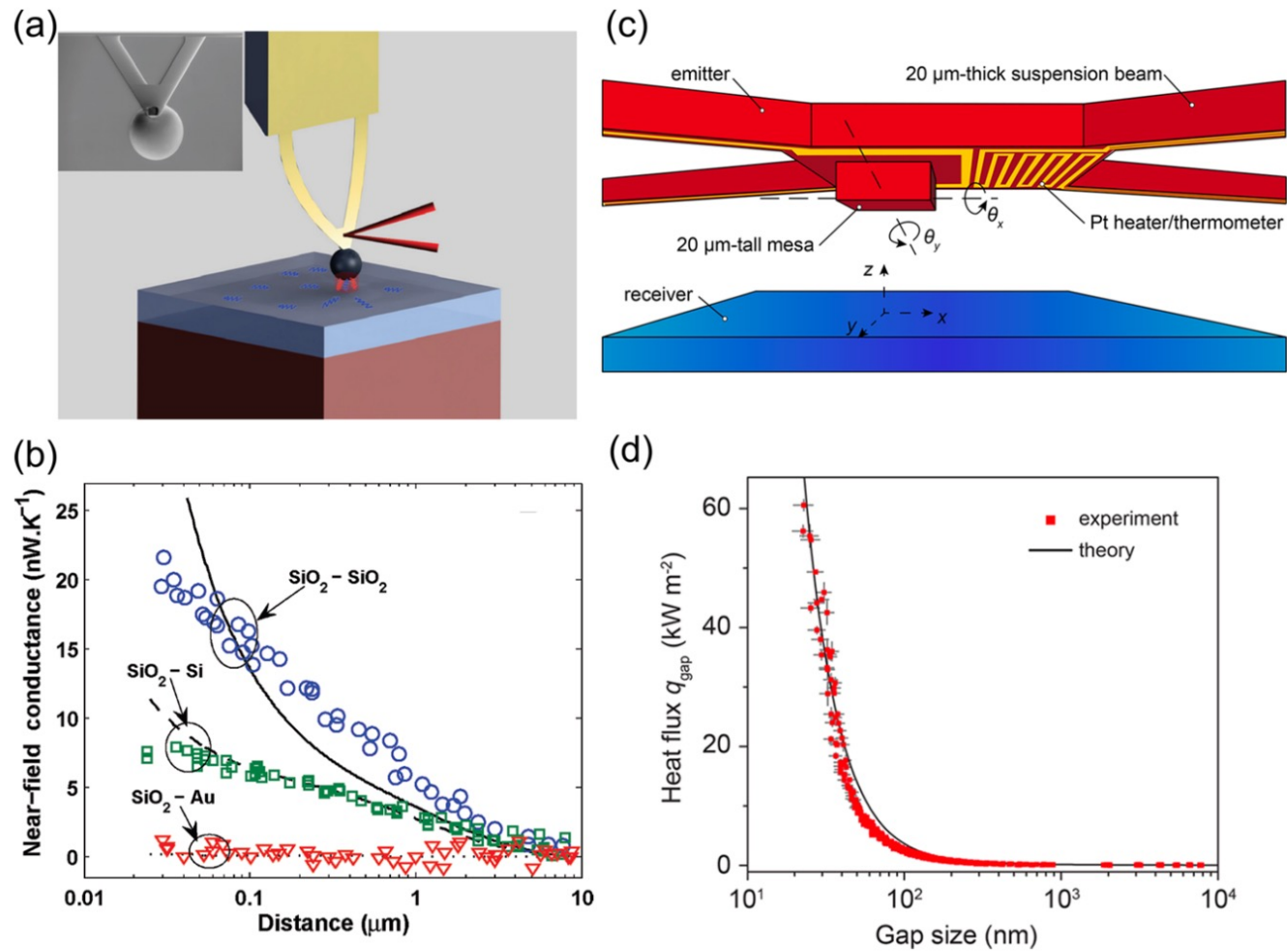
Increased radiation heat transfer at μm scale gaps is due to the **resonant tunnelling** of electromagnetic surface phonon polaritons between two closely spaced objects.

When d is lower than $1 \mu\text{m}$, the radiative heat transfer :

$$Q_{th} \propto \frac{1}{d^2}$$

- JP Mulet et al., *Microscale Thermophysical Engineering*, 6:209–222, 2002

- A. Narayanaswamy et al., *Breakdown of the Planck blackbody radiation law at nanoscale gaps*, *Appl Phys A* (2009) 96: 357–362



J. C. Cuevas, F. J. García-Vidal, Radiative Heat Transfer.
ACS Photonics. **5**, 3896–3915 (2018)

Temperature fluctuations in microstructures

Temperature fluctuations

$$\Delta T_{n,rms} = \sqrt{\frac{4k_B T^2}{G_{th}}} \sqrt{\Delta f}$$

G_{th} : thermal conductance

In radiation limit conditions (vacuum, no contact)

$$G_{th} = 4\sigma T^3 \quad \text{with } \sigma = 5.7 \cdot 10^{-8} \text{ W / m}^2 \text{ K}^4$$

$$\text{at } T=300 \text{ K} \quad \Delta T_{n,rms} = \sqrt{\frac{3 \cdot 10^{-21}}{A}} \sqrt{\Delta f} \quad \propto L^{-1}$$

For a cube of side x , in vacuum, at 300K, for a bandwidth of 100 Hz:

$x = 1 \text{ mm}$	$A = 6 \cdot 10^{-6} \text{ m}^2$	$\Delta T = 0.5 \text{ } \mu\text{K}$
$x = 10 \text{ } \mu\text{m}$	$A = 6 \cdot 10^{-10} \text{ m}^2$	$\Delta T = 50 \text{ } \mu\text{K}$
$x = 1 \text{ } \mu\text{m}$	$A = 6 \cdot 10^{-12} \text{ m}^2$	$\Delta T = 0.5 \text{ mK}$

Radiation conduction limit is the **ultimate resolution limitation** in MEMS bolometers, if all other heat transfer mechanism removed by design

Paul W. Kruse, "Can the 300-K radiating background noise limit be attained by uncooled thermal imagers?", Proc. SPIE 5406, Infrared Technology and Applications, 437 (August 30, 2004)

F. Niklaus et al., "MEMS-based uncooled infrared bolometer arrays: a review", Proc. SPIE 6836, MEMS/MOEMS (2008)

Dynamics of thermal systems (1D)

$$Q_{th} = G_{th}(T_1 - T_2)$$

$$Q_{th} = C_{th} \frac{dT}{dt} = c_v \rho V \frac{dT}{dt}$$

$$\frac{\partial^2 T(x, t)}{\partial x^2} = \frac{\rho c_v}{\kappa_{th}} \frac{\partial T}{\partial t}$$

$$T(t) = \frac{T_1 + T_2}{2} (1 - e^{-\frac{t}{\tau}})$$

Time constant

$$\tau_{th} = \frac{C_{th}}{G_{th}} = \frac{m c_v}{G_{th}}$$

$$\tau_{conduction} = \frac{L m c_v}{\kappa_{th} A}$$

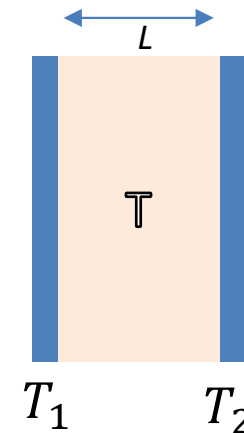
$$\tau_{conduc} = \frac{\rho c_v L \cdot V}{2 \kappa_{th} A}$$

$\propto L^2$

Dissipated power per volume

$$\frac{Q_{th}}{V} = \frac{1}{\tau_{th}} \propto \frac{1}{L^2}$$

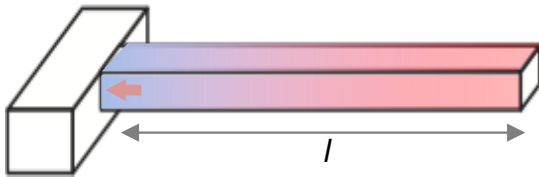
fast systems -> requires a lot of energy per volume



- κ_{th} : thermal conductivity in [W/(m.K)]
- c_v : specific heat capacity [J/(kg.K)]
- C_{th} : heat capacity [J/K]
- A : the area [m²]
- ρ : Density (kg/m³)
- Q : heat transferred per unit time [W]

Cooling time constant of a cantilever due to longitudinal conduction

Time constant cantilevers that are cooled by conduction along the material (no convection). Heated at the free end.



$$\frac{\partial^2 T(x, t)}{\partial x^2} = \frac{\rho c_v}{\kappa_{th}} \frac{\partial T}{\partial t} = D_{th} \frac{\partial T}{\partial t}$$

Lumped model
Bi << 1

Thermal diffusivity $D_{th} = \frac{\kappa_{th}}{\rho c_v}$

$$l_{th_diff} = \sqrt{D_{th} t}$$

thermal diffusion length t: time

Thermal time constant for this beam

$$\tau = \frac{\rho c_v l^2}{2 \kappa_{th}}$$

	$D_{th} [10^{-6} \text{ m}^2/\text{s}]$	$l=10 \mu\text{m}$	$l=100 \mu\text{m}$	$l=1000 \mu\text{m}$
Si	102	0.5 μs	50 μs	5 ms or f=200Hz
Pt	25	2 μs	0.2 ms	20 ms or f=50Hz
SiO ₂	0.6	83 μs	8.3 ms	830 ms or f=1Hz
Water	0.14	0.35 ms	35 ms	3.5 s

Can't propagate change in temperature faster than this!

Table: thermal diffusion times for various cantilever length (+water for comparison)

Bolometers

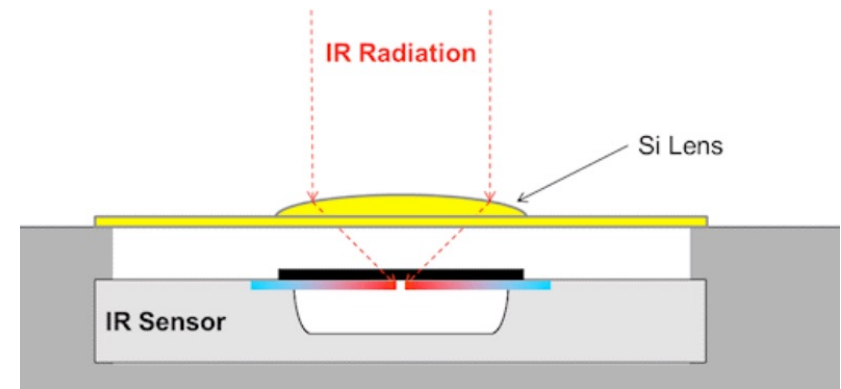
Principle: The IR radiation is absorbed on a thermally isolated absorber leading to a few mK increase in T .

The temperature rise $T - T_0$ is proportional to the intensity of the incident IR radiation Φ_{rad}

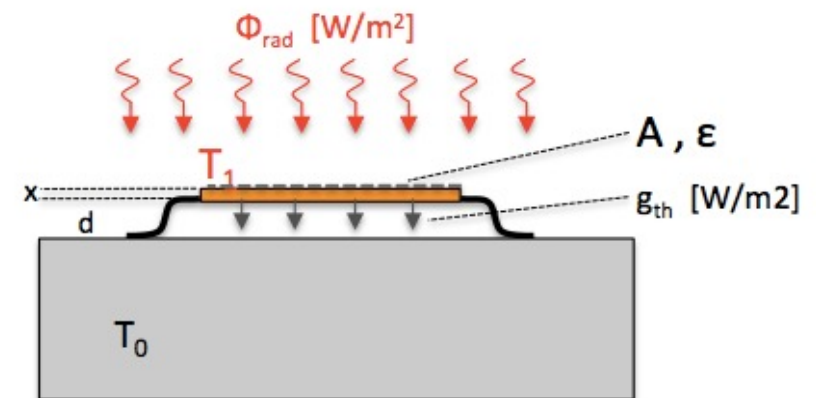
The temperature variation is measured by the change in resistance of the thermally insulated sensing pixel (membrane)

Sensor Temperature Balance:

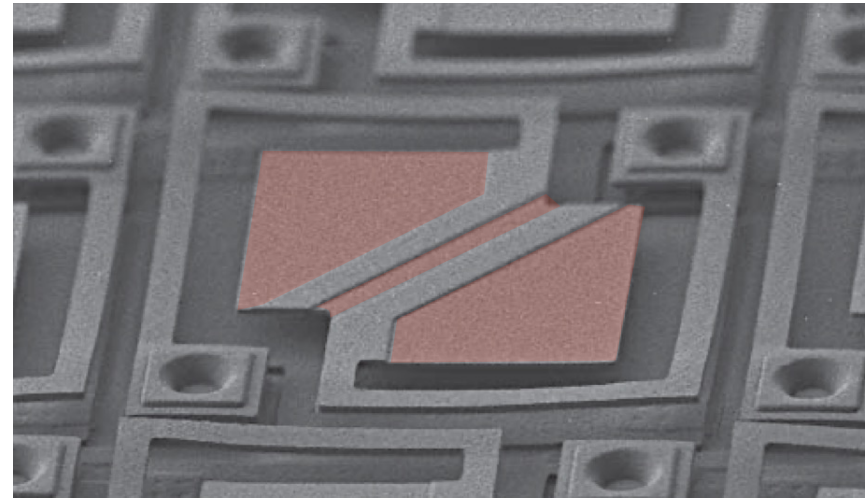
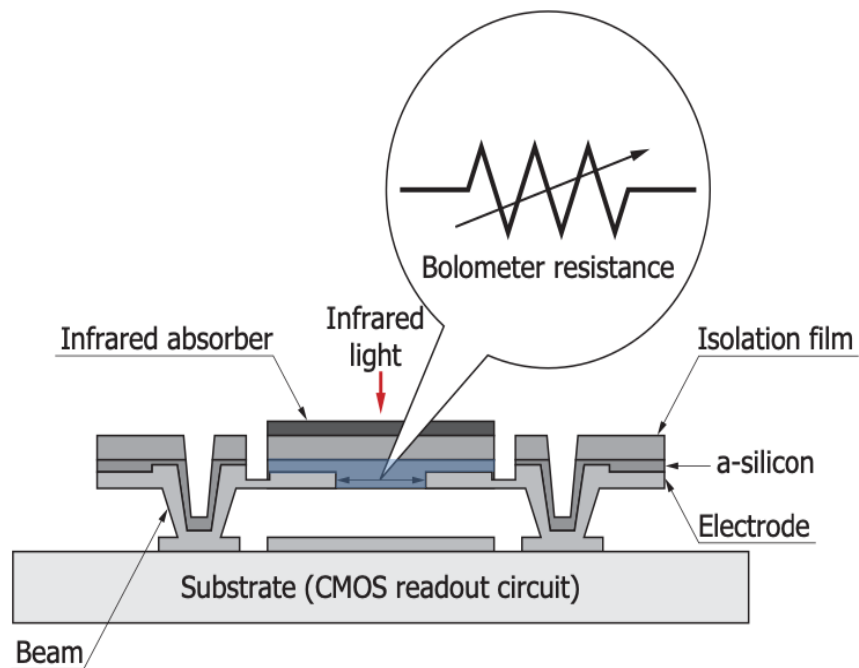
Incident IR radiation $\leftrightarrow$ conduction to substrate



<https://jsss.copernicus.org/articles/2/85/2013/jsss-2-85-2013.pdf>

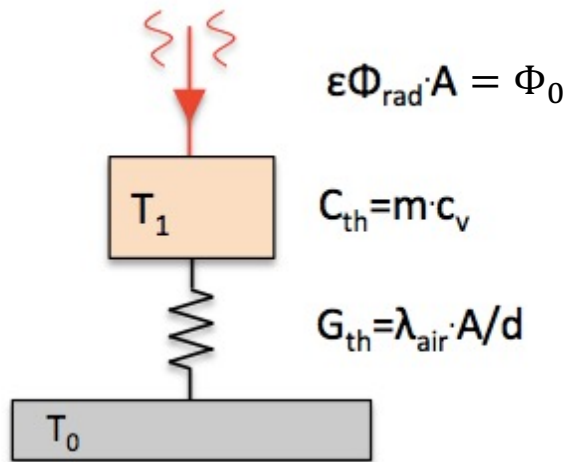


Bolomètre (matrix -> imaging)



- Typical pixel size is 10 μm to 50 μm
- pixel count ranges from 80x60 to >HD
- CMOS below for ΔR measurement
- Air-dominated heat conduction (not suspension arms)

Bolometer: equivalent thermal model



Time constant (general)

$$\tau_{th} = \frac{C_{th}}{G_{th}} = \frac{mc_v}{G_{th}}$$

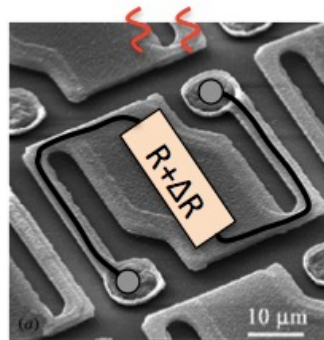
Time constant (conduction)

$$\tau_{th} = m c_V \frac{d}{\lambda_{air} A} \sim L^2$$

DC sensitivity: $T - T_0 = \frac{\Phi_0}{G_{th}} = \Phi_0 \frac{d}{\lambda_{air} A} \sim L^{-1}$

For d/A , trade-off speed vs sensitivity!

d : air gap (see next slide)
 λ_{air} : thermal conductivity air
 α_r : thermal coeff of resistance
 Φ_0 : absorbed IR flux



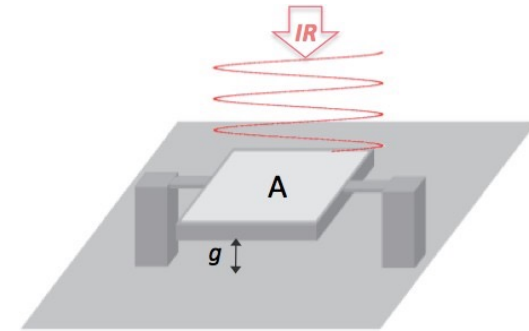
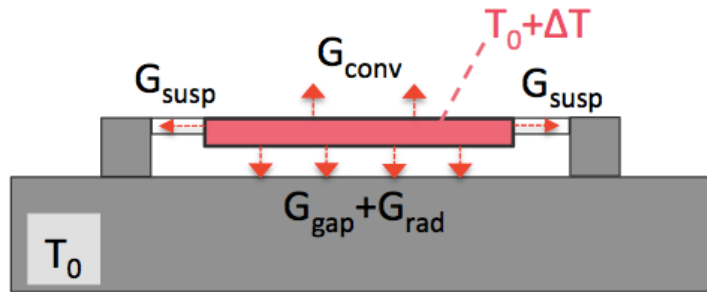
Change in sensor R with ΔT

$$\frac{\Delta R}{R} = \alpha_R (T - T_0) = \frac{\Phi_0 \alpha_R}{G_{th}} = \frac{\varepsilon \Phi_{\text{rad}} \alpha_R}{\lambda_{air}} d$$

sensitivity depends on:

- α_R
- λ_{air}
- d

Heat losses in surface-micromachined bolometers



Num: plate of 200 μm x 200 μm gap=2 μm
Si suspension beams (2x) 200 x 15 x 1 μm

Conductance due to: top surface convection

Si suspensions

Radiation

Air gap conduction

$$G_{th} = h_k \cdot A = 4 \cdot 10^{-7} \text{ WK}^{-1}$$

$$G_{th} = k_{Si} \cdot A/l = 6 \cdot 10^{-6} \text{ WK}^{-1}$$

$$G_{th} = 4A \cdot \epsilon \sigma T^3 = 4 \cdot 10^{-7} \text{ WK}^{-1}$$

$$G_{th} = \kappa_{air} \cdot A/d = 5 \cdot 10^{-4} \text{ WK}^{-1}$$

- **Air gap conduction** is the **dominant** heat loss mechanism in most bolometers (which affects both the *sensitivity* and the *time constant*)
- Detail: Some groups modulate the thermal parameters: they control the gap (using electrostatic force) to trade-off sensitivity vs. bandwidth

J. Talghader, J. Phys D: Appl. Phys. 37 (2004) R109

Micro-PCR for DNA amplification

PCR: DNA amplification by thermal cycling

Most common method is 384 well plate that is heated and cooled at a few °C/s

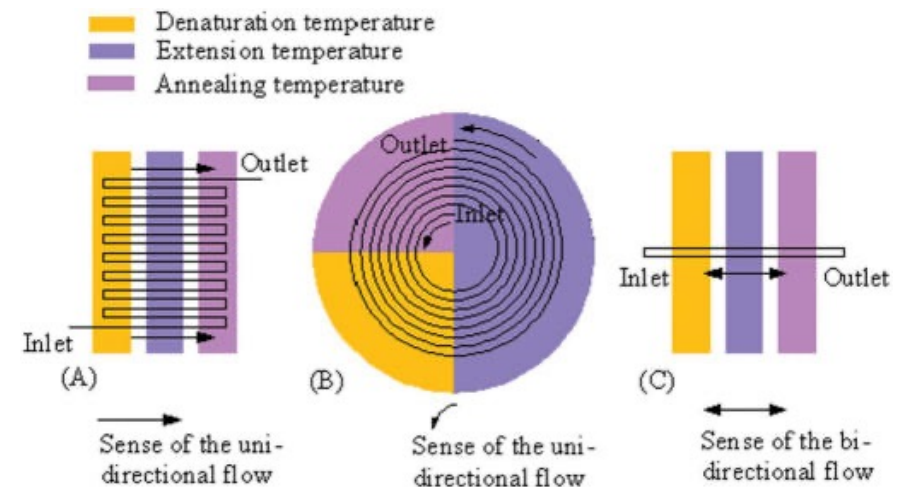
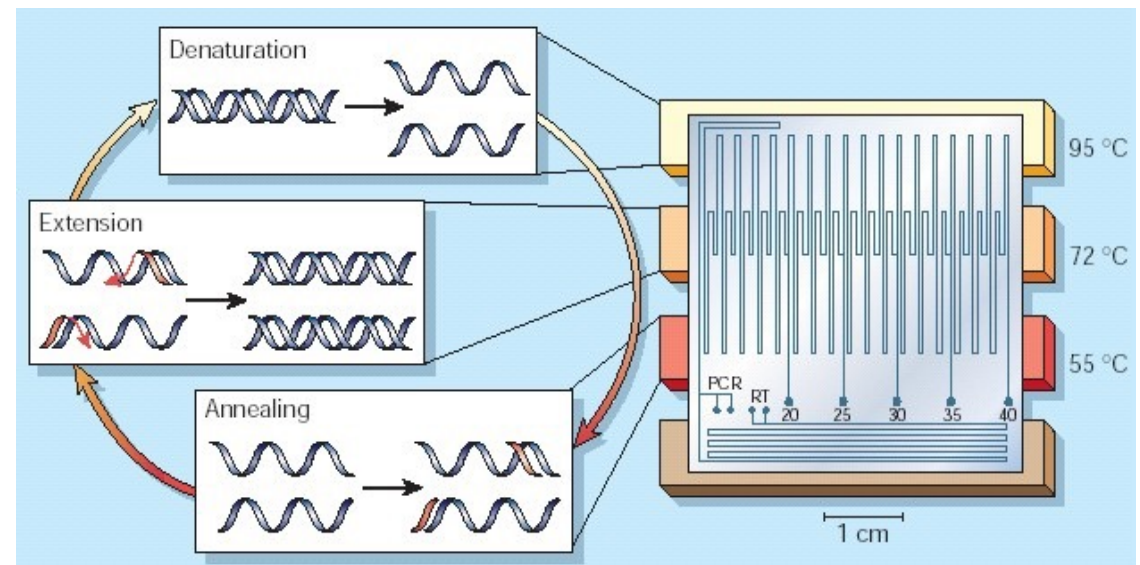
Using microfluidics (scaling) allows for very rapid thermal cycling

faster cycling → faster amplification

Two approaches:

- (a) small volume chamber with integrated heater,
- (b) continuous flow PCR with thermal gradient on chip

P. Obeid, "Microfabricated Device for DNA and RNA Amplification by Continuous-Flow Polymerase Chain Reaction and Reverse Transcription-Polymerase Chain Reaction with Cycle Number Selection", Anal. Chem. 75 (2003) 288



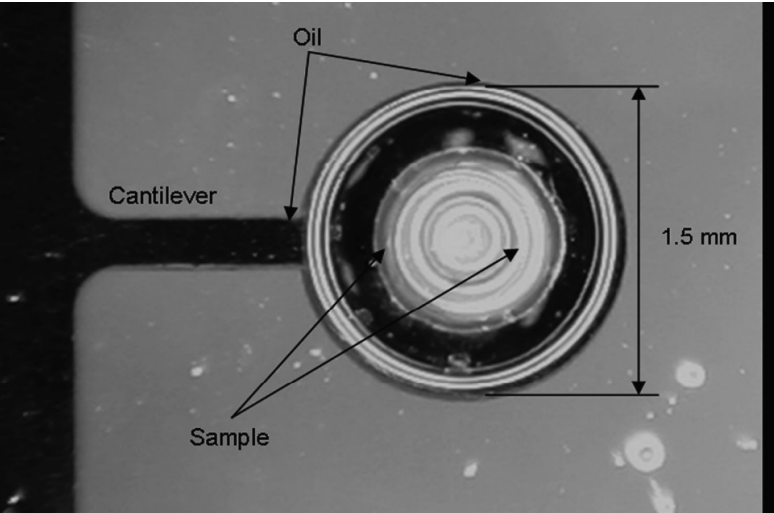
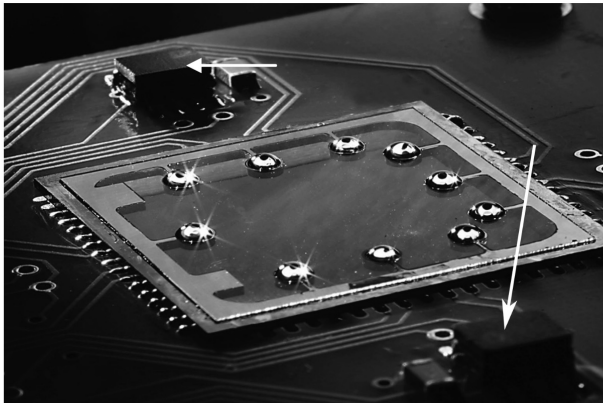


Figure 3. Optical photograph of the sample encapsulated by oil (edges pointed to by arrows) placed above the heater and separated from it by a microscope cover slip. The hemispherical oil shape formed a lens which magnified the sample.



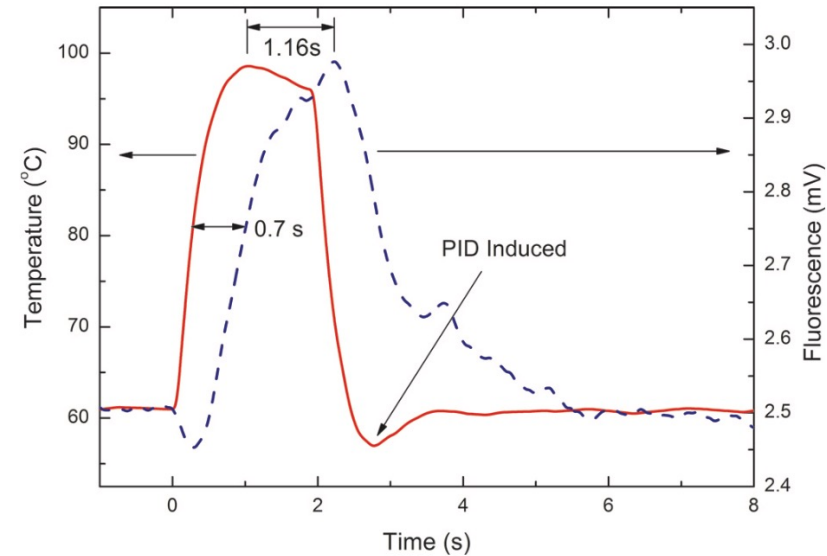
Microphotograph of a fabricated chip 24.2 × 24.2 mm in size, soldered to a PCB. The chip consists of 10 individually controlled heaters.

P. Neuzil, C. Zhang, J. Pipper, S. Oh, L. Zhuo,
 Ultra fast miniaturized real-time PCR: 40 cycles in less than six minutes.
Nucleic Acids Research. **34**, e77 (2006).

Table 1. Electrical and thermal parameters of the nanoPCR device itself

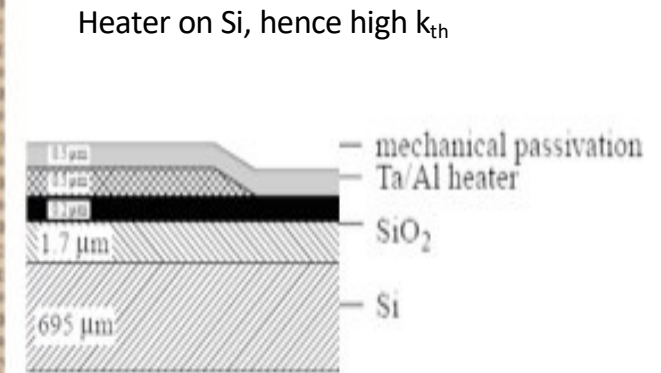
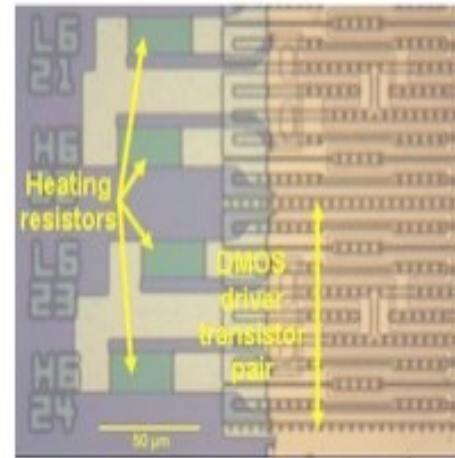
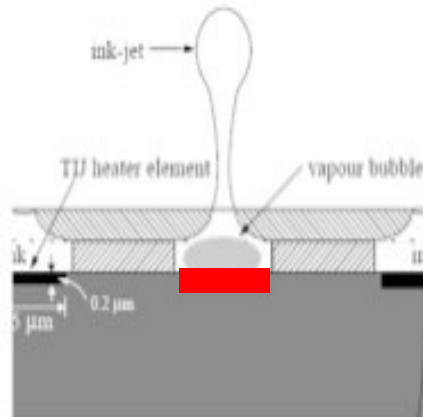
Sensor resistance (at 25°C)	427Ω
Heater resistance (at 25°C)	141Ω
System temperature response	11 mV/°C
PCR thermal conductance	0.42 mW/°C
PCR thermal capacitance	1.5 mJ/°C
PCR thermal time constant	0.28 Hz
Heating rate from 60 to 95°C	175°C/s
Cooling rate from 95 to 60°C	−125°C/s

$$\tau = RC$$

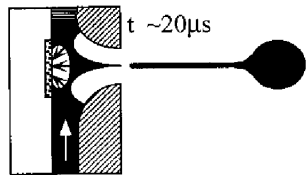
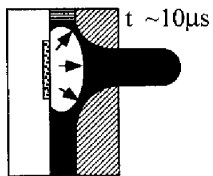
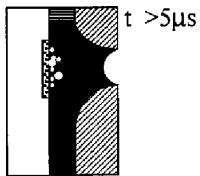


Thermal Inkjet (HP+Canon)

Use the μs time constant
in micro-system



Heater on Si, hence high k_{th}



HP data :

Resistor : tantalum,
Current pulse
Heating at
Surface power density
Internal pressure
Ejection speed

30 x 15 μm

250 mA

10^8 degree/second

10^9 W/m²

130 bar (cracks...)

15 m/s (aging, abrasion...)

32 pl droplets at rate of 6000 Hz

30 nm thickness
during 2.5 μs

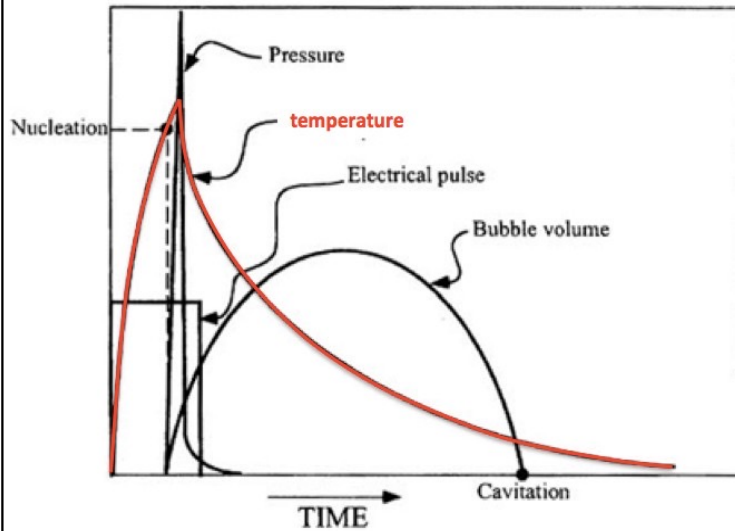
R=8 Ω

$$\text{Calculated power : } p_{in} = 8 \cdot 0.25^2 = 500 \text{ mW} \quad p_{in} / A = 1.1 \cdot 10^9 \text{ W / m}^2$$

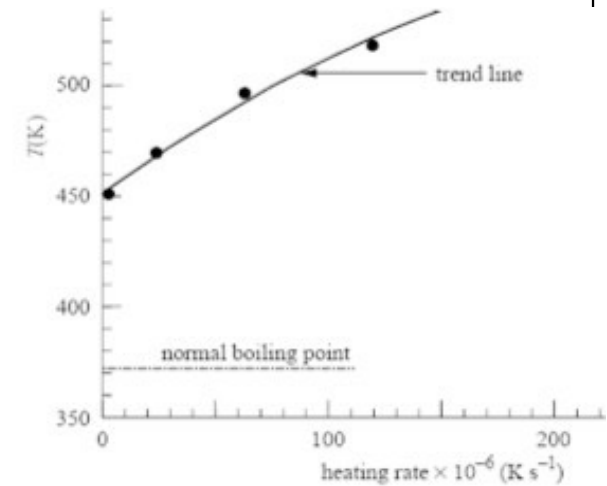
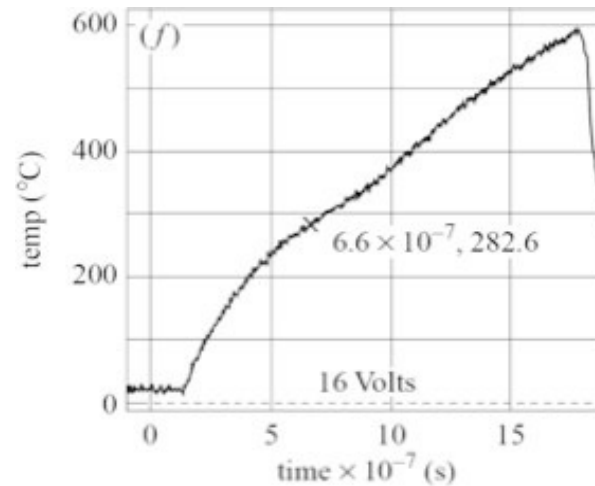
need very high heating rate ($>10^6$ K/s) to achieve supercritical heating to ensure rapid bubble collapse

Need very high cooling to enable rapid repeat: ie need high thermal conductivity from heater to substrate

Planar heater modeling to determine time constant



<https://www.imaging.org/IST/IST/Resources/Tutorials/Inkjet.aspx>



Heating rate and its effect on the nucleation temperature (15 μs pulse)

$$T = R_{th} C_{th} = 5 \mu s$$

Energy efficacy on thermal inkjets:

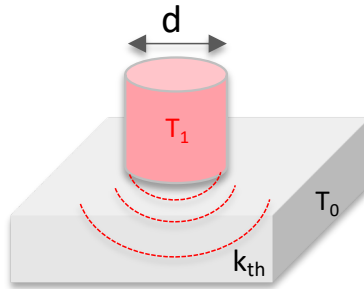
- Electrical energy input to eject one drop : $I^2 R t = 3 \cdot 10^{-7} J$
- Kinetic energy (assuming 40 μm diameter) = $0.5 m \cdot v^2 = 3 \cdot 10^{-12} J$

$$\Rightarrow E_{in} / E_{out} \text{ ratio is } 10^{-5}$$

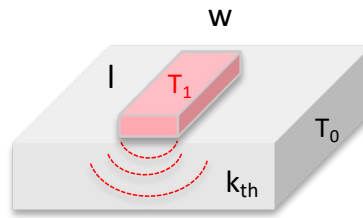
0.001 % thermal to kinetic energy conversion !

Planar heater modeling to get time constant

Very approximate...



$$R_{th} = \frac{1}{2d k_{th}}$$



$$R_{th} \approx \frac{1}{4\sqrt{lw} k_{th}}$$

$$\Delta T = R_{th} P_{in} = \frac{P_{in}}{4\sqrt{lw} k_{SiO_2}}$$

on SiO ₂	$\Delta T = 4500^\circ\text{C}$	??
on Si	$\Delta T = 35^\circ\text{C}$	??

Both solutions are wrong because the surface is 1.7 μm of SiO₂ on Si substrate



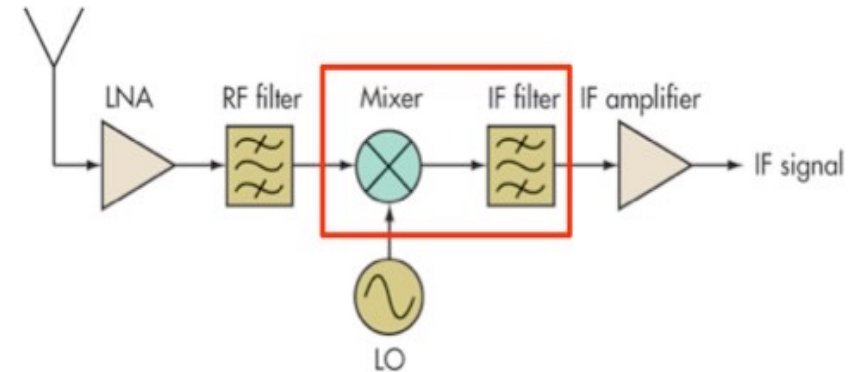
$$\Delta T \approx P_{in} \left(\frac{h}{w l k_{SiO_2}} + \frac{1}{4\sqrt{lw} k_{Si}} \right)$$

$\Delta T = 1500^\circ\text{C}$

$$P_{in}=500\text{mW} \quad l=30\mu\text{m} \quad w=15\mu\text{m} \quad h=1.7\mu\text{m}$$

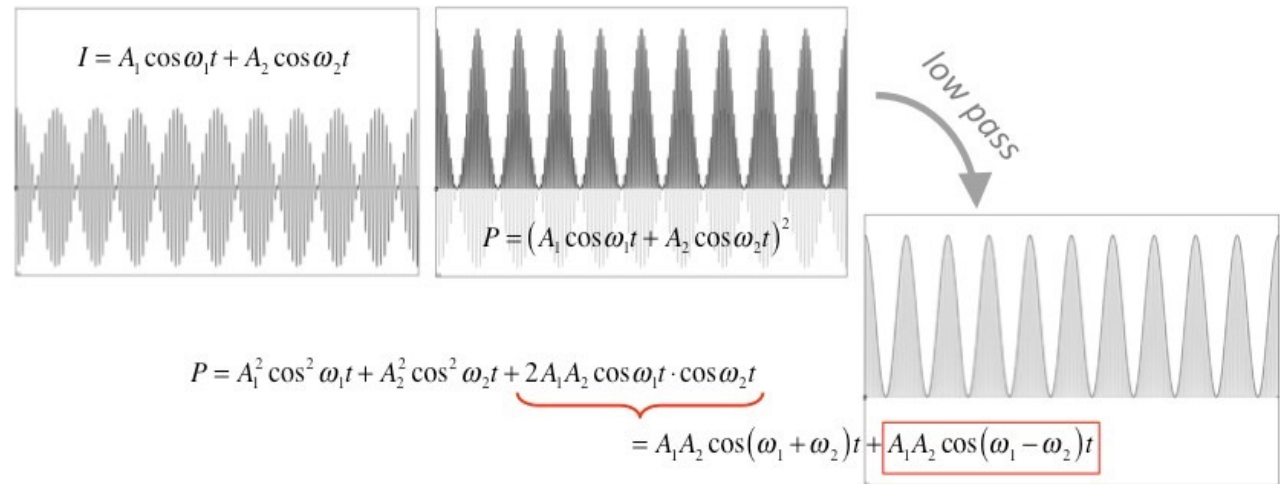
High frequency thermal mixing. How fast can a thermal system be?

Concept: use a thermo-mechanical device as IF (intermediate frequency) stage for RF radio.
The mixer multiplies the RF frequency with the reference RF oscillator (LO) in order to extract the IF signal.
Typically GHz RF frequencies, and MHz IF freq



Use an **electro-thermal actuator** that is driven by the **sum** of high frequency signal currents, **RF + LO**

As the **power** is proportional to the **square of the current**, the power modulation contains both a **$f_1 + f_2$** and **$f_1 - f_2$** terms



High frequency thermal mixing

$$P(t) = RI^2 = R(I_1 \cos \omega_1 t + I_2 \cos \omega_2 t)^2 = I_1^2 \cos^2 \omega_1 t + 2I_1 I_2 \cos \omega_1 t \cos \omega_2 t + I_2^2 \cos^2 \omega_2 t$$

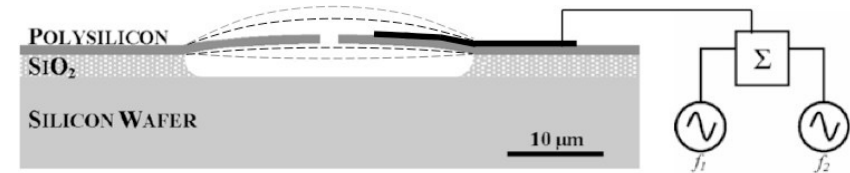
with $2I_1 I_2 \cos \omega_1 t \cos \omega_2 t = I_1 I_2 \cos(\omega_1 + \omega_2)t + I_1 I_2 \cos(\omega_1 - \omega_2)t$

The device is a small **bimorph membrane** consisting of a polysilicon layer and a metal layer.

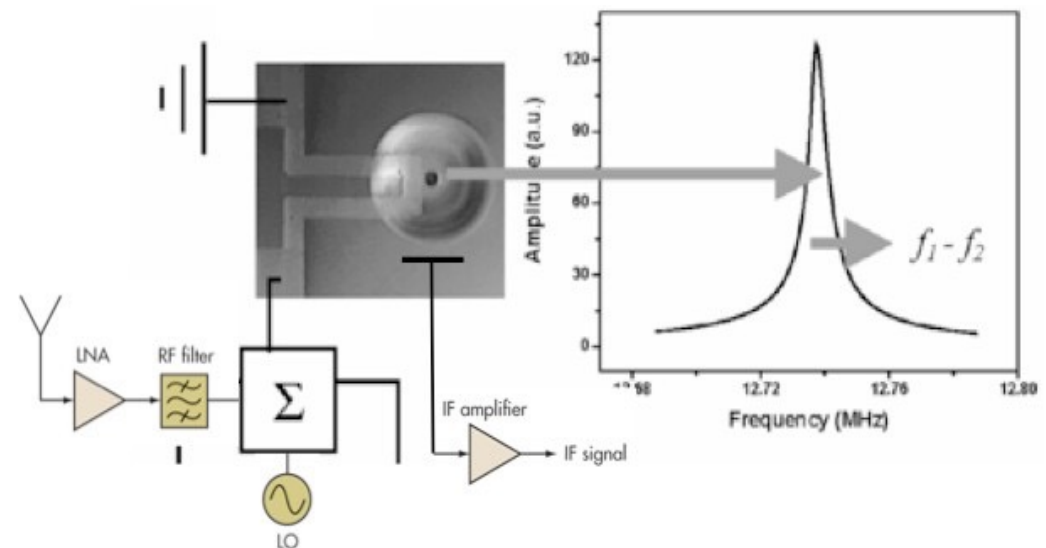
Current in the metal strip provokes local heating and **downward** deflection of the membrane (with capacitive detection of movement)

- **MHz thermal bandwidth** can be reached because of **downscaling** to 10 μm

Appl. Phys. Lett., 83, 18 (2003)



Thermal $\rightarrow$ deflection $\rightarrow$ change in capacitance



Electro-Thermal actuators

3 main types

- Bimorph
- Hot/cold arm
- Chevron

- Low Voltage
- High force
- No magnetic field
- No high electric fields
- Slow!
- Very low efficiency

Review article: A. Potekhina and C. Wang, "Review of Electrothermal Actuators and Applications". *Actuators*. **8**, 69 (2019).

Electro-thermal actuators: Thermal bimorph

- 2 materials with different coefficients of thermal expansion α_1 and α_2 .
- One serves as the heater
- What ideal thickness? And thickness ratio?

Curvature Γ of a bimorph of thickness h_1 and h_2 , with Young's modulus E_1 and E_2 :

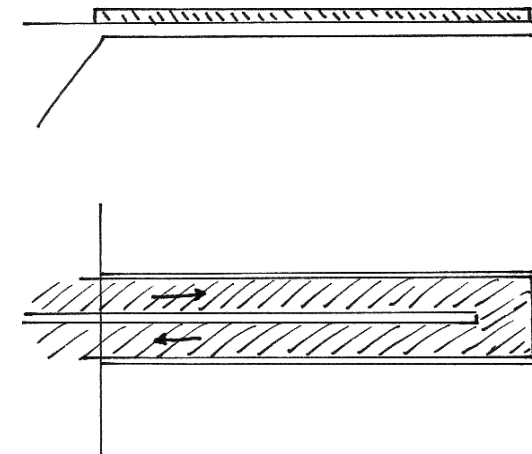
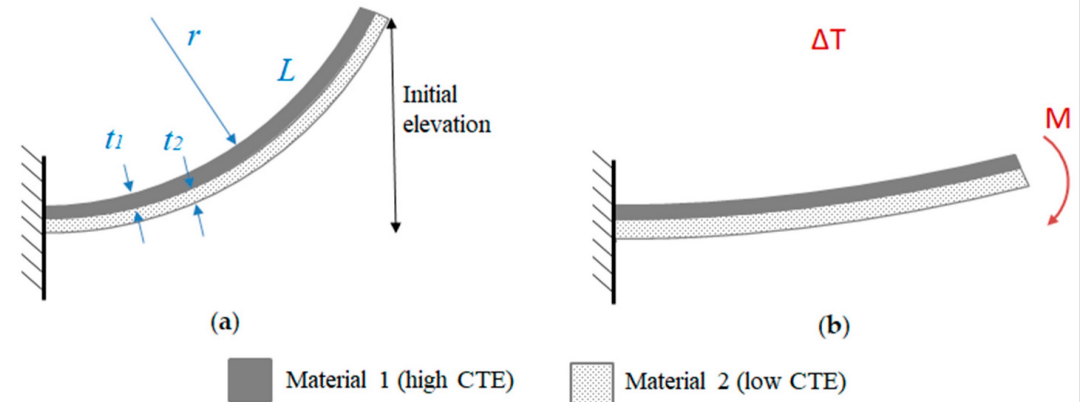
Change temperature ΔT

Thermal expansion coefficient difference: $\Delta\alpha = \alpha_1 - \alpha_2$

$$\Gamma = \frac{1}{r} = \frac{6(h_1 + h_2) \cdot \Delta\alpha \cdot \Delta T}{4h_1^2 + 4h_2^2 + 6h_1h_2 + \frac{h_1^3 E_1}{h_2 E_2} + \frac{h_2^3 E_2}{h_1 E_1}}$$

Largest curvature when: $h_1 E_1 = h_2 E_2$

$$\frac{h_1}{h_2} = \frac{E_2}{E_1} = k$$



Side view and top view of a cantilever bimorph

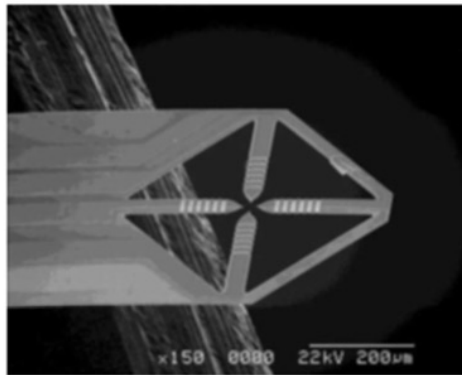
Electro-thermal actuators: Thermal bimorphs

If optimize thickness, get:

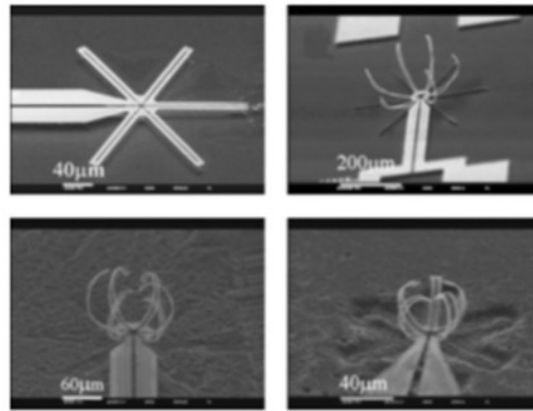
$$\Gamma(\Delta T) = \frac{0.7 \cdot \Delta \alpha}{h_{tot}^2} \Delta T$$

$$\Gamma \propto \frac{1}{h^2}$$

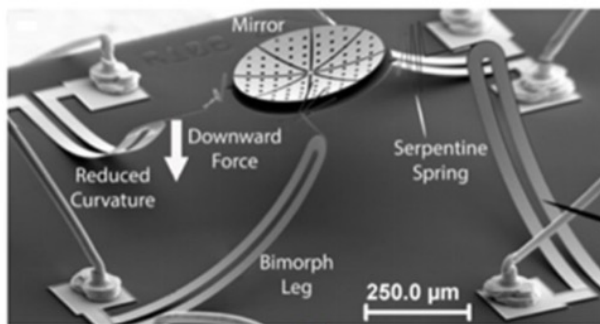
Bimorph bending angle
scales favorably to small
dimensions
(but force does not)



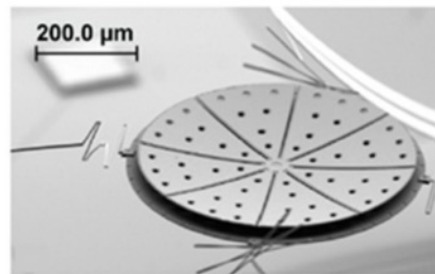
(a)



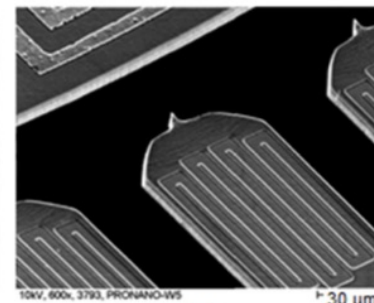
(b)



(c)



(d)



(e)

A. Potekhina, Review of Electrothermal Actuators and Applications. *Actuators*. **8**, 69 (2019).

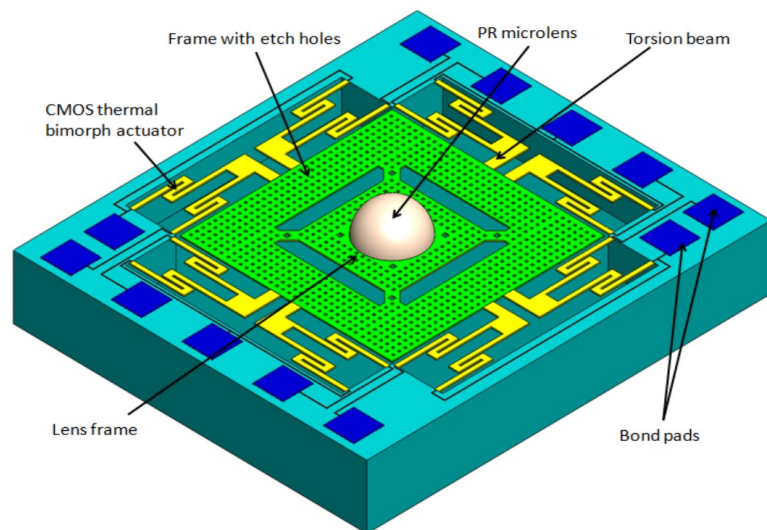
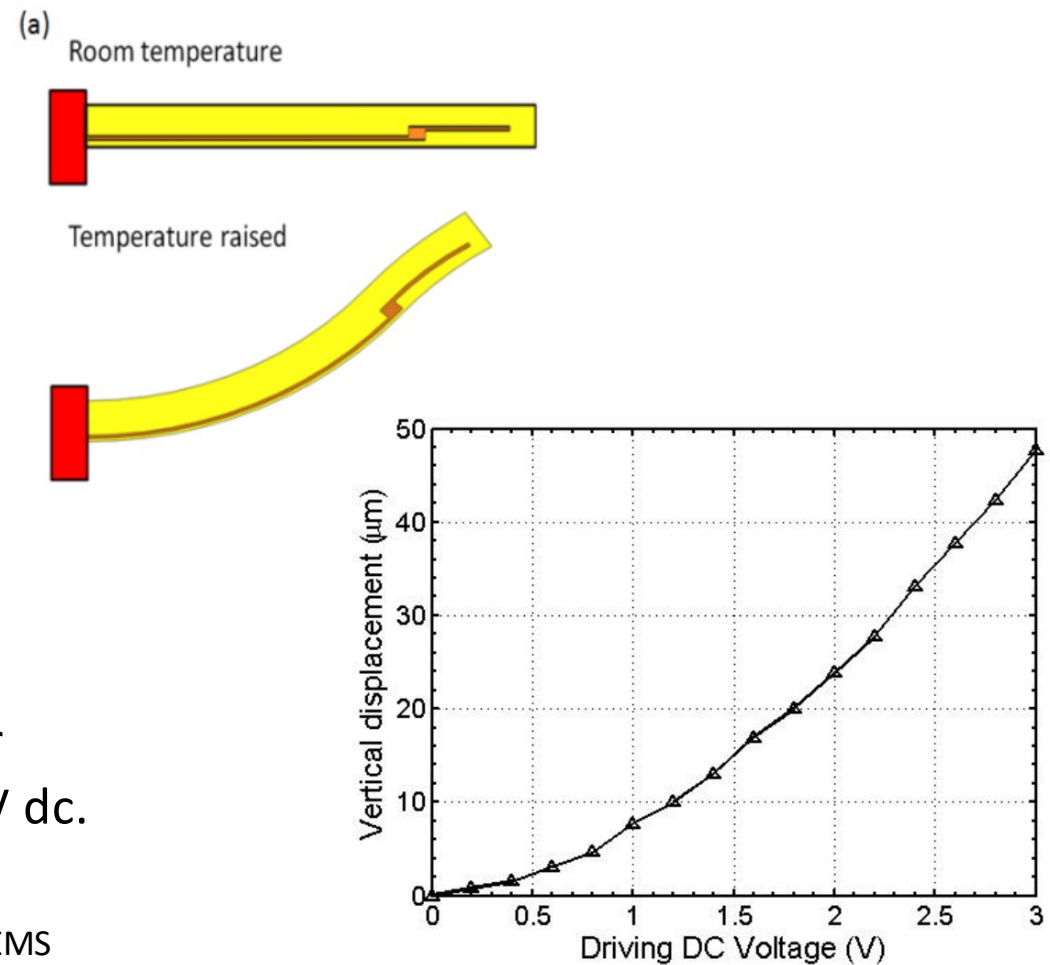


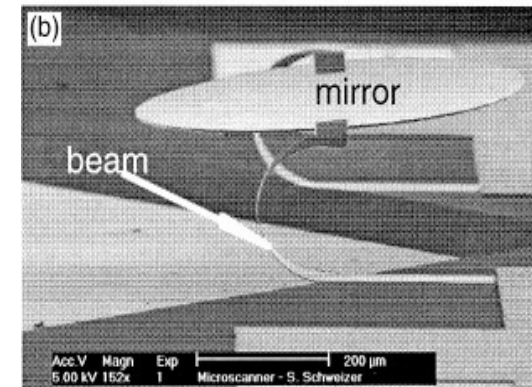
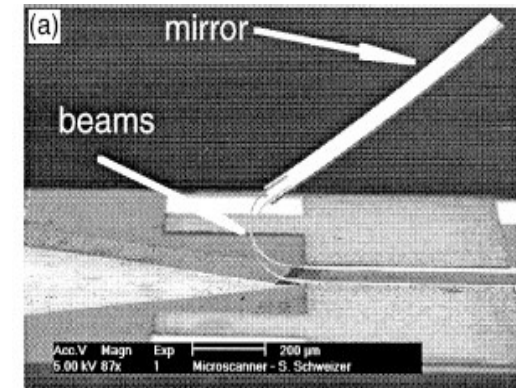
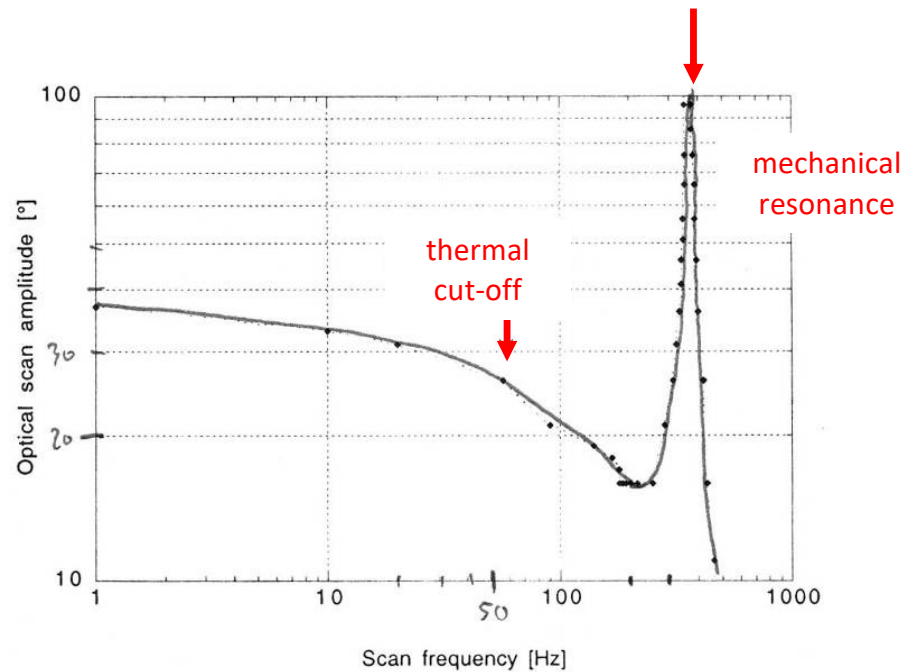
Fig. 1. Schematic diagram of the proposed 3-D scanning microlens, where the lens frame is actuated by 4 sets of CMOS thermal bimorph actuators.

Vertical displacement of $47\ \mu\text{m}$ and power consumption of 139 mW is obtained at 3 V dc.

K. H. Koh, C. Lee, J.-H. Lu, C.-C. Chen, "Development of CMOS MEMS thermal bimorph actuator for driving microlens" in *16th International Conference on Optical MEMS and Nanophotonics* (2011), pp. 153–154.



Thermomechanical transfer function

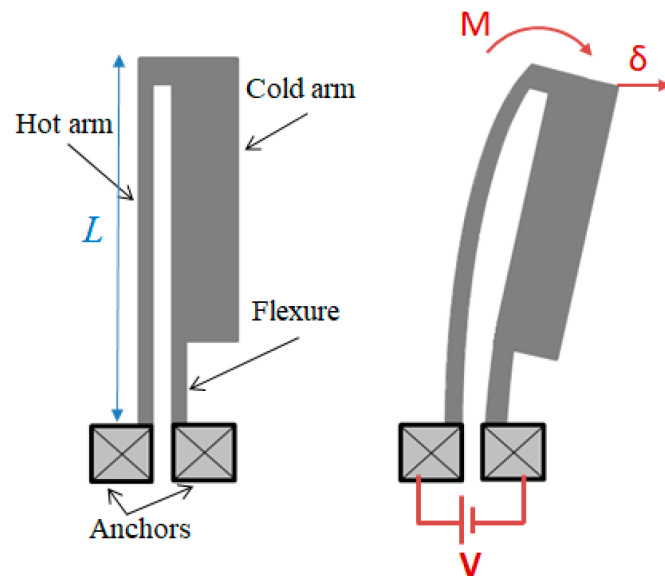


Dynamical response of bimorph thermal actuator. Thermal cut-off is 1st order function is in this case at about 50 Hz and there is a 2nd order mechanical resonance at about 400 Hz (from Schweizer paper).

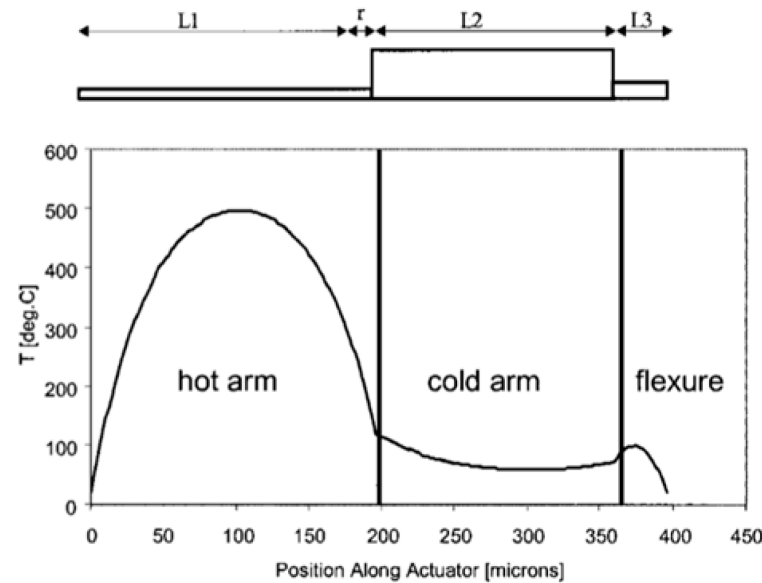
- Thermally actuated optical microscanner with large angle and low consumption, S. Schweizer et al., Sensors and Actuators (1999)

Horizontal thermal actuator - U-shaped actuator (hot/cold arm)

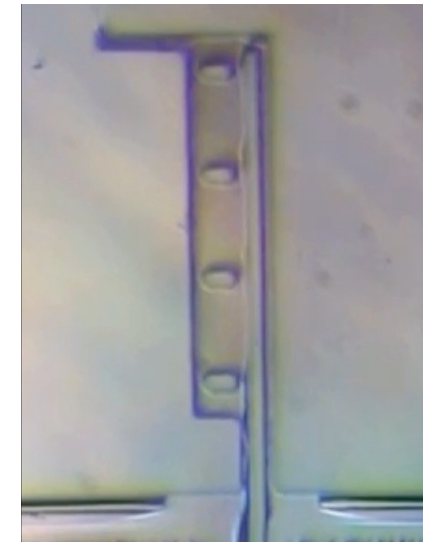
Principle: asymmetric beam size => asymmetric temperature (due to difference in heating and in losses)



(a)



(b)



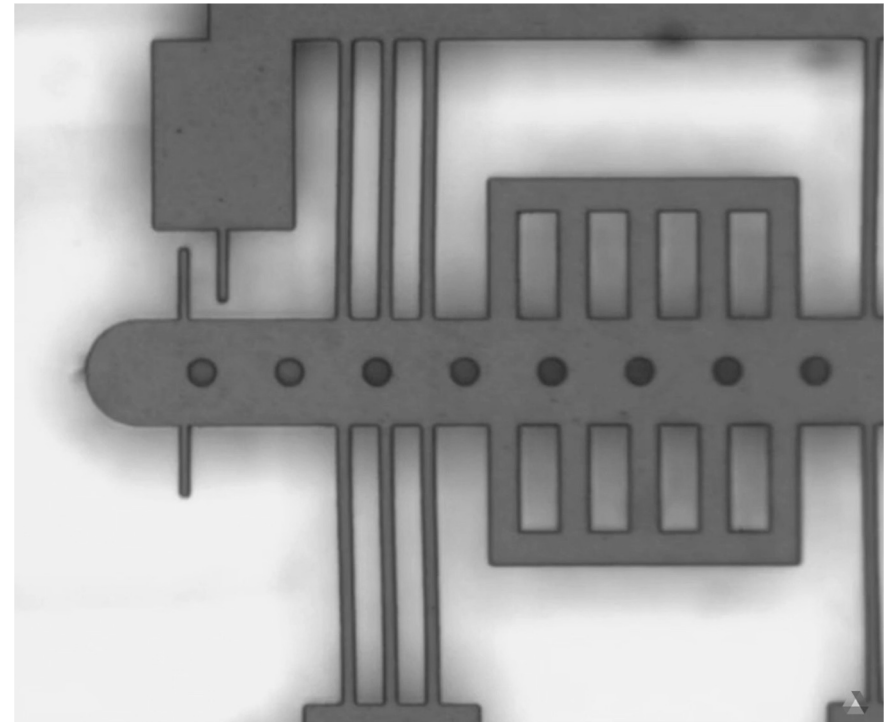
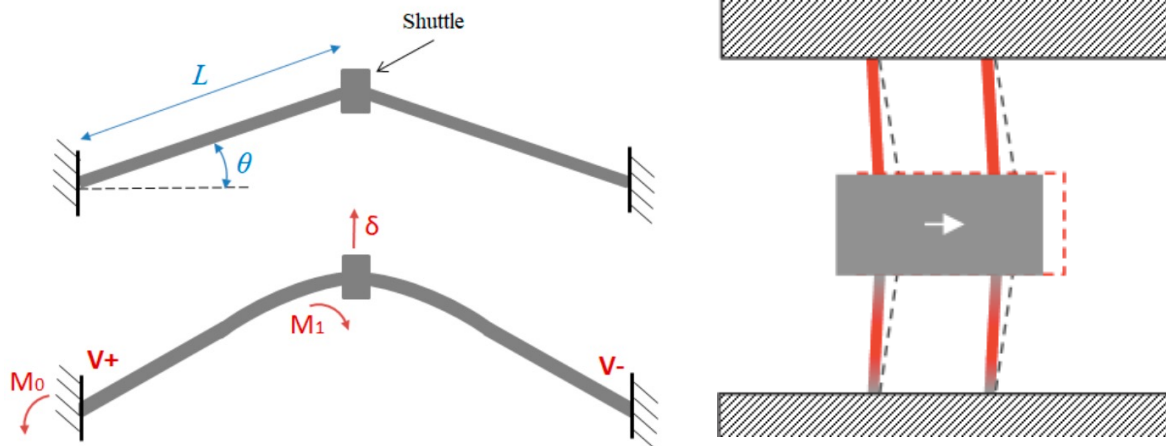
The arm with large area has lower electrical resistance and dissipates more heat and thus remains cooler than the other «hot» arm.

- R. Syme, Long-travel electrothermally driven resonant cantilever microactuators, *J. Micromech. Microeng.* 12 (2002) 211–218
- N. Mankame et al., Comprehensive thermal modelling and characterization of an electro-thermal- compliant microactuator, *J. Micromech. Microeng.* 11 (2001) 452–462

Heat flow dominated by conduction in the 1-2 μm gap between substrate and actuator: the cold arm is well cooled.

Horizontal thermal actuators - V-beam (or Chevron) actuator

- Doubly clamped beam with a "shuttle" at the middle
- Expansion make the shuttle moving laterally
- Relatively large displacement obtained

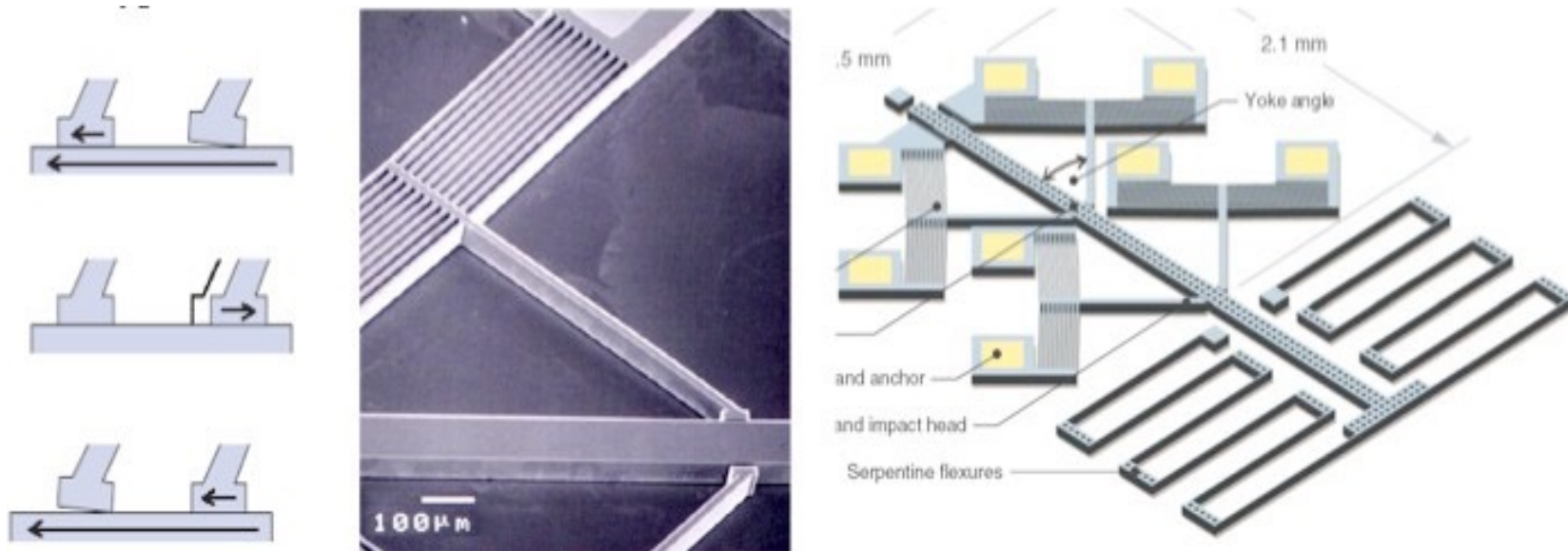


Small displacement, high force

Lott et al., "Modeling the thermal behavior of a surface-micromachined linear-displacement thermomechanical microactuator", Sensors and Actuators A: Physical, Volume 101, 2002, Pages 239-250

Horizontal thermal actuators

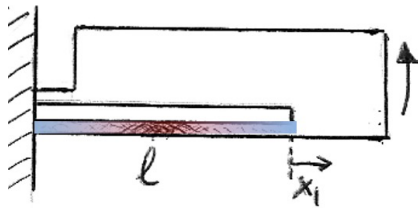
Inchworm type:



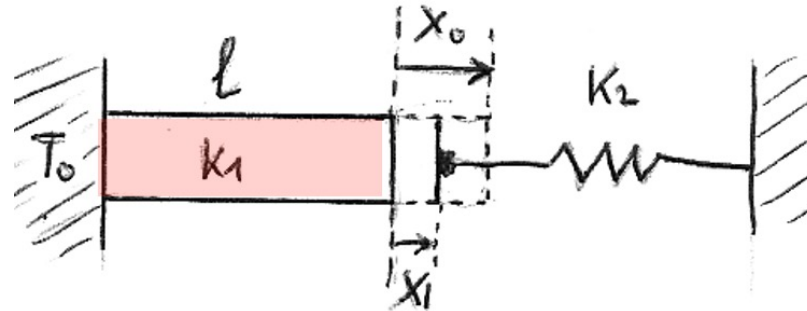
- J. Maloney, J. Micromech. Microeng. 14 (2004) 226
- D. de Voe, "Thermal issues in MEMS and microscale systems", IEEE Trans. On Comp. and Pack Tech. 25 (2003) 576

Energy density in thermo-mechanical actuators

Actual Device



Simplified Model: 1D, uniform ΔT , load is spring k_2



Free beam thermal expansion

$$x_0 = l \cdot \alpha \cdot \Delta T_{average}$$

Constrained beam expansion

$$x_1 = \frac{k_1}{k_1 + k_2} x_0$$

Thermomechanical work energy on k_2

$$W_{mec} = \frac{1}{2} k_2 x_1^2 = \frac{1}{2} \frac{k_1 k_2}{k_1 + k_2} x_0^2$$

when $k_2 \rightarrow 0$ $W_{mec} \rightarrow 0$: no work if there is no load

when $k_2 \rightarrow k_1$ $W_{mec} \rightarrow \frac{1}{4} k_1 x_0^2$: **maximal efficacy when $k_1 = k_2$**

when $k_2 \rightarrow \infty$ $W_{mec} \rightarrow 0$: no work done if the actuator displacement is completely blocked

Energy density in thermo-mechanical actuators

Our model assumption: $k_2 = k_1$ (i.e. maximal efficacy)

- thermomechanical energy $W_{tmech} = \frac{1}{4} k_1 x_0^2 = \frac{1}{4} k_1 l^2 \left(\alpha \cdot \Delta T_{average} \right)^2$
- thermomechanical energy density $w_{tmech} = \frac{1}{4} E \left(\alpha \cdot \Delta T_{average} \right)^2$ E: elastic modulus

Numerical value for Silicon beam: $\alpha = 2.7 \cdot 10^{-6}$ $\Delta T_{max} = 300^\circ C$ $E = 190 \text{ GPa}$

For an actuator beam of dimensions $20 \times 2 \times 300 \mu m^3$

$$\Delta T_{average} = \frac{2}{3} \cdot \Delta T = 200^\circ C \quad \Rightarrow \quad w_{tmech} \cong 10^5 \text{ J / m}^3 \quad W_{tmech} = 2 \cdot 10^{-11} \text{ J}$$

=1 bar

At 100 Hz actuation frequency $P_{mec} = f_0 \cdot W_{tmech} \cong 2 \cdot 10^{-9} \text{ Watt of mechanical output}$

Efficiency of thermo-mechanical actuators

Let's compute the dissipated thermal power (to reach $T_{\max}$ in clamped beam):

$$P_{therm} = \frac{2\kappa_{th} w h}{l} \Delta T_{max} \quad P_{therm} = 10 \text{ mW}$$

=> Power efficiency of the electrothermal actuator

$$\frac{P_{mec}}{P_{therm}} = 10^{-6}$$

Compare with the mechanical energy stored in a resonator beam:

$$\text{Example: } 0.1 \text{ Nm, } x = 50 \text{ } \mu\text{m} \quad E_{mec} = 10^{-10} \text{ J}$$

Now calculate mechanical dissipation and then compare with thermal energy needed to maintain oscillation:

$$Q = 2\pi \frac{E_{mec}}{E_{diss}} \quad E_{diss} = \frac{2\pi E_{mec}}{Q}$$

$$Q=100, f=500 \text{ Hz} \quad P_{diss}=14 \text{ nW} \quad P_{therm} = 10 \text{ mW}$$

ie need 10 mW thermal powr to sustain 13 nW mechanical power...